

Device Modeling Report

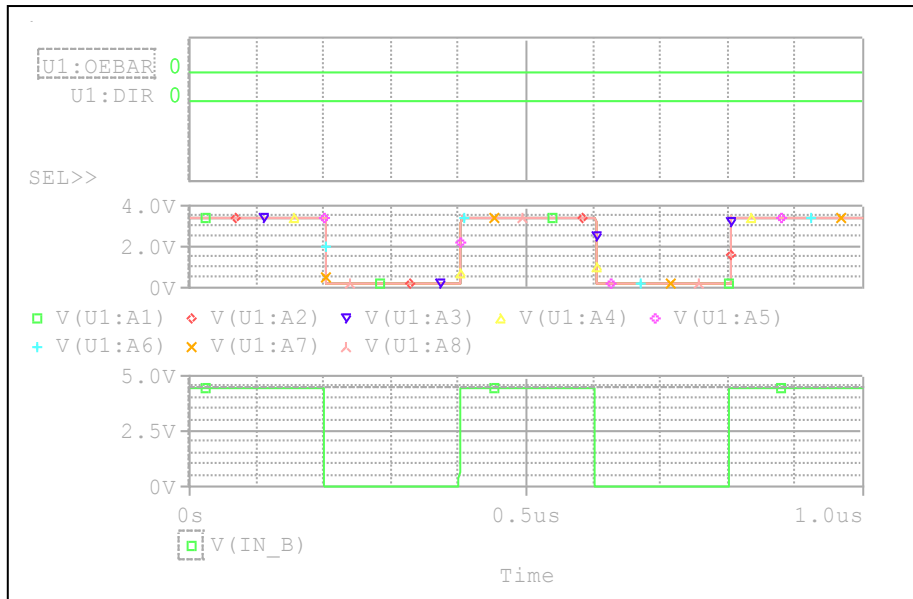
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC74VCX245FT
MANUFACTURER : TOSHIBA



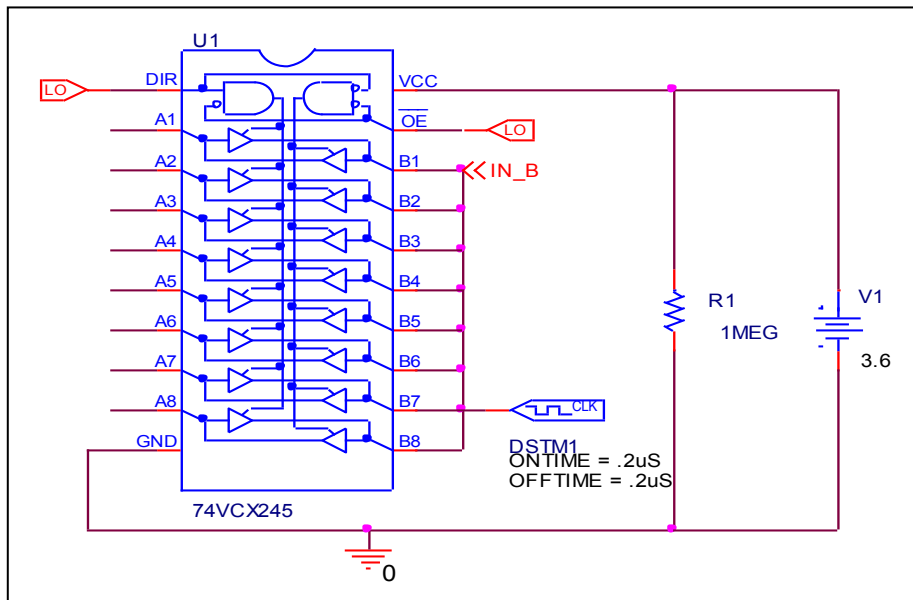
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit



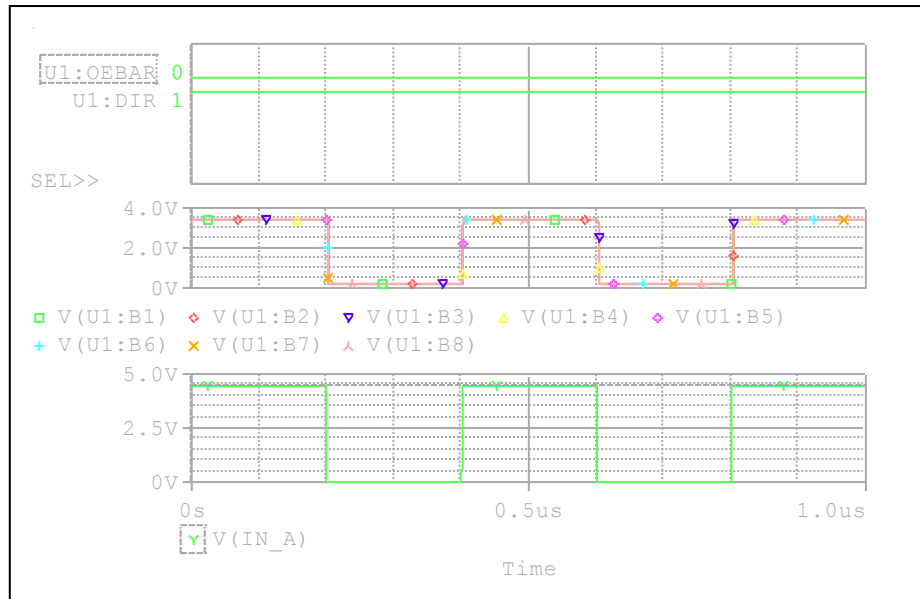
Comparison table

Function : A BUS = OUTPUT, B BUS = INPUT

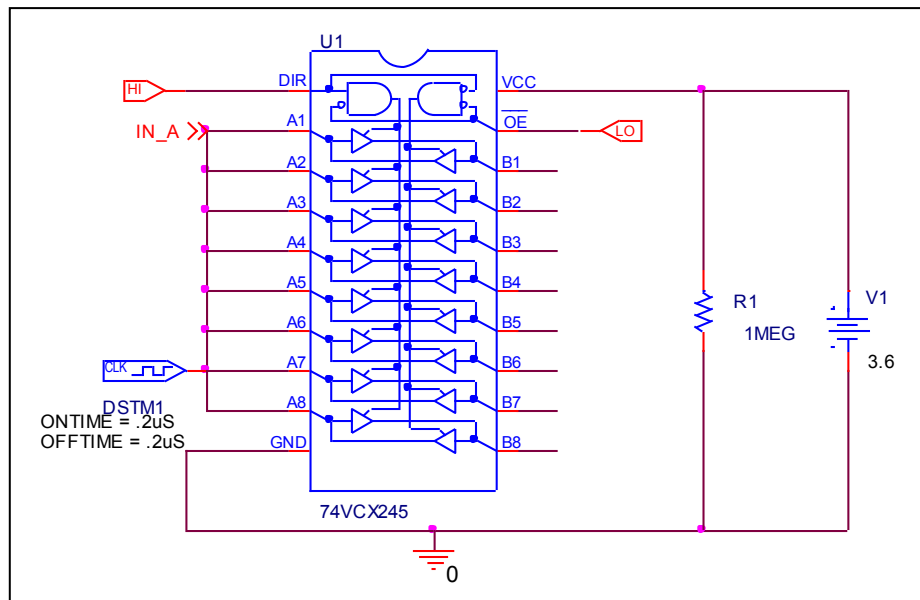
Input		Output		%Error
OE	DIR	Measurement	Simulation	
L	L	A=B	A=B	0

Truth Table

Circuit simulation result



Evaluation circuit



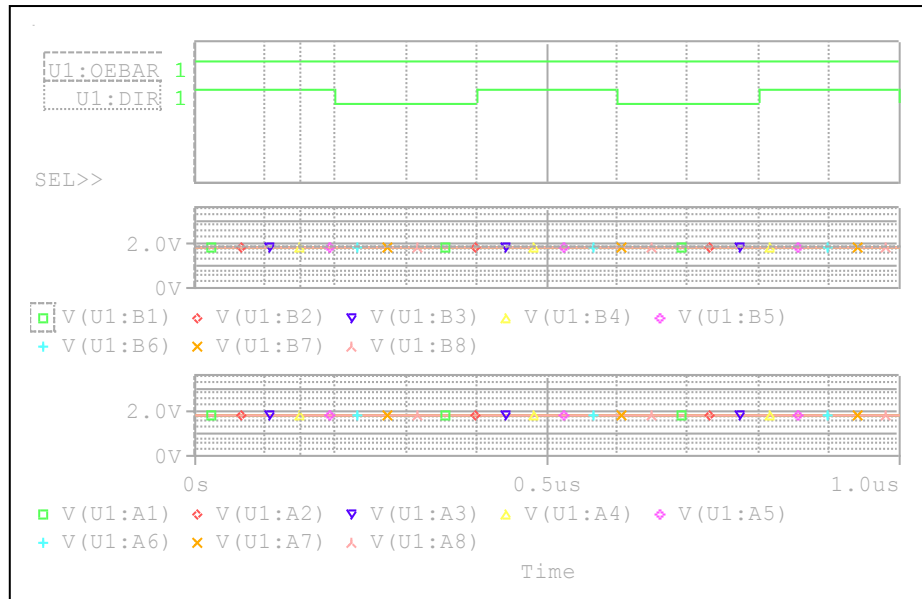
Comparison table

Function : A BUS = INPUT, B BUS = OUTPUT

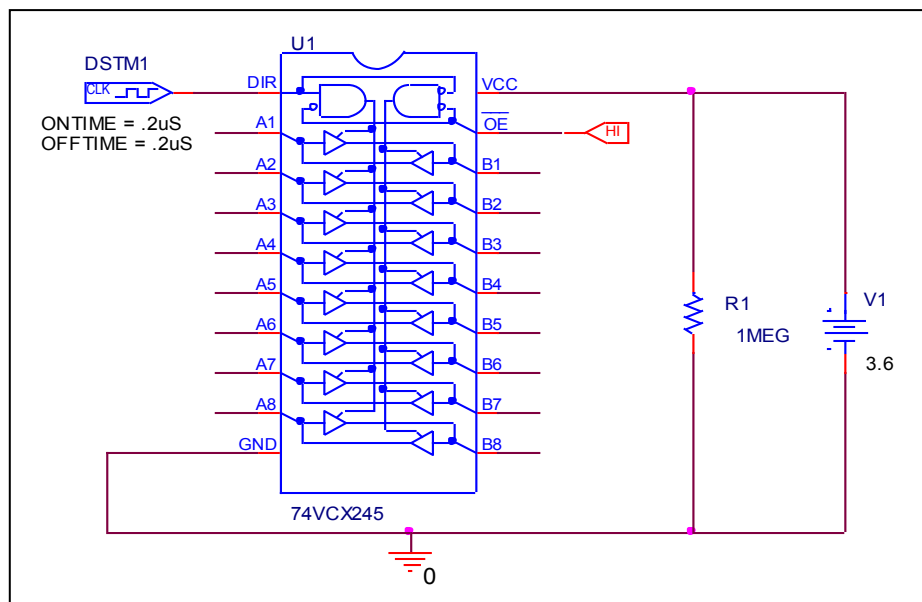
Input		Output		%Error
OE	DIR	Measurement	Simulation	
L	H	B=A	B=A	0

Truth Table

Circuit simulation result



Evaluation circuit



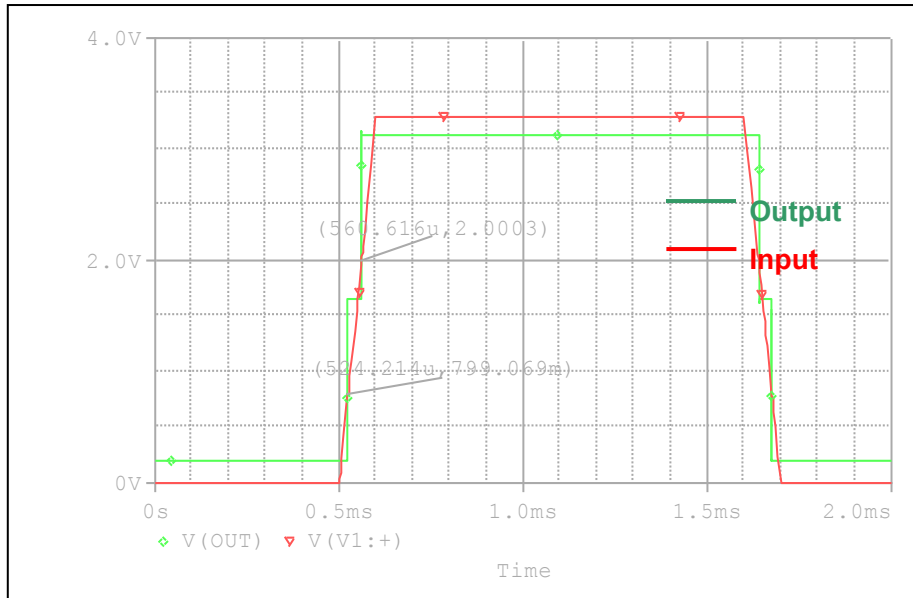
Comparison table

Function : A BUS and B BUS = HIGH IMPEDANCE

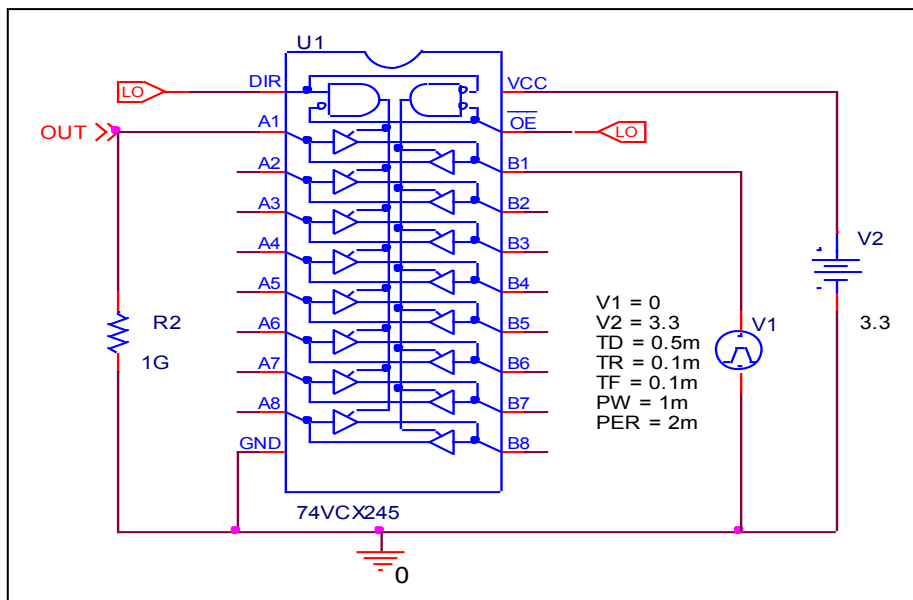
Input		Output		%Error
OE	DIR	Measurement	Simulation	
H	X	Z	Z	0

High Level and Low Level Input Voltage ($2.7\text{ V} < V_{CC} \leq 3.6\text{ V}$)

Circuit simulation result



Evaluation circuit

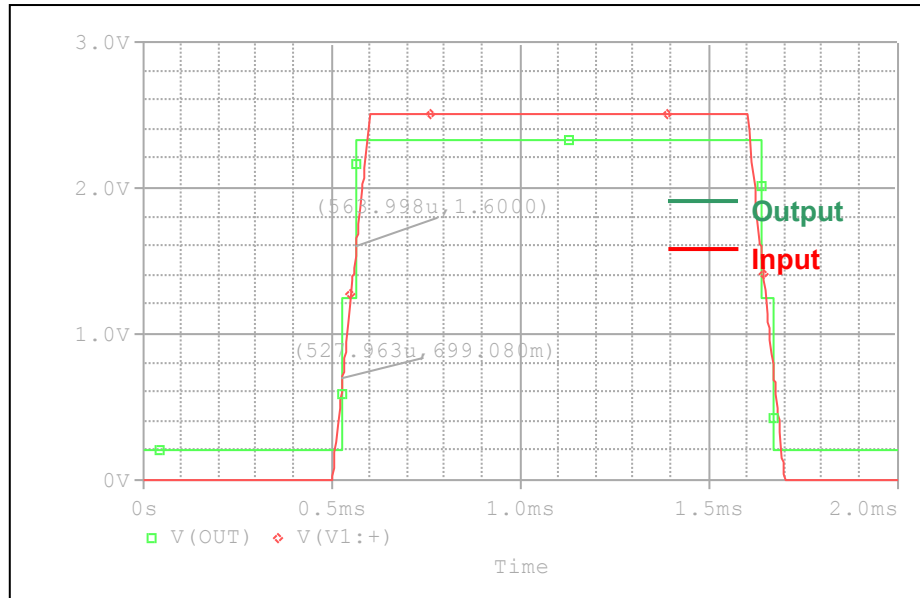


Comparison table

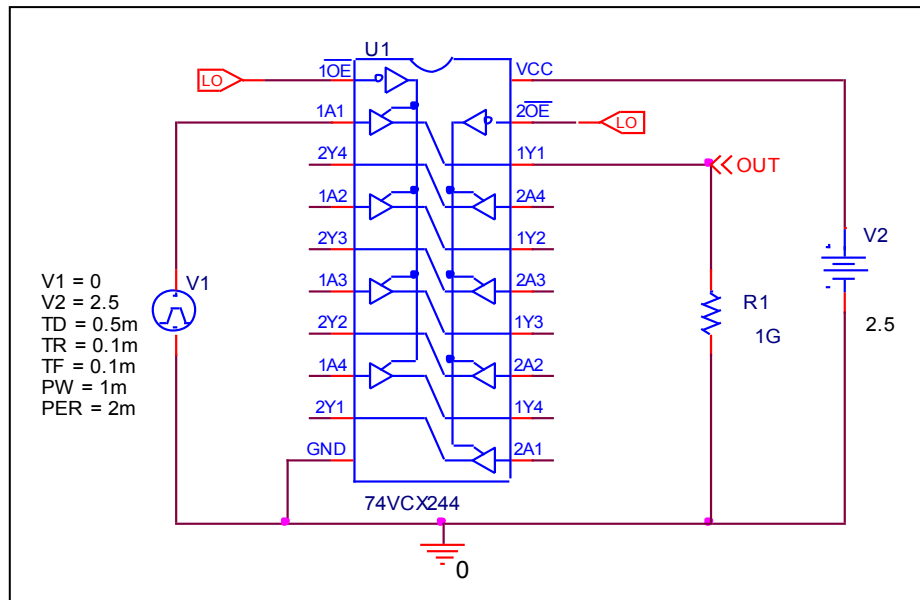
$V_{CC} = 3.3\text{ V}$	Measurement	Simulation	%Error
$V_{IH}\text{ (V)}$	2	2	0
$V_{IL}\text{ (V)}$	0.8	0.799069	-0.116

High Level and Low Level Input Voltage ($2.3\text{ V} \leq V_{CC} \leq 2.7\text{ V}$)

Circuit simulation result



Evaluation circuit

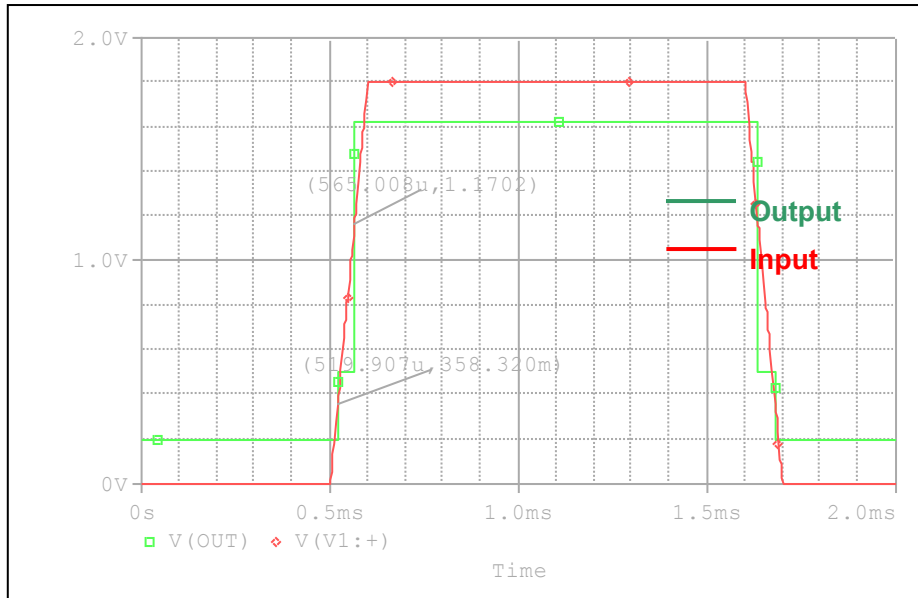


Comparison table

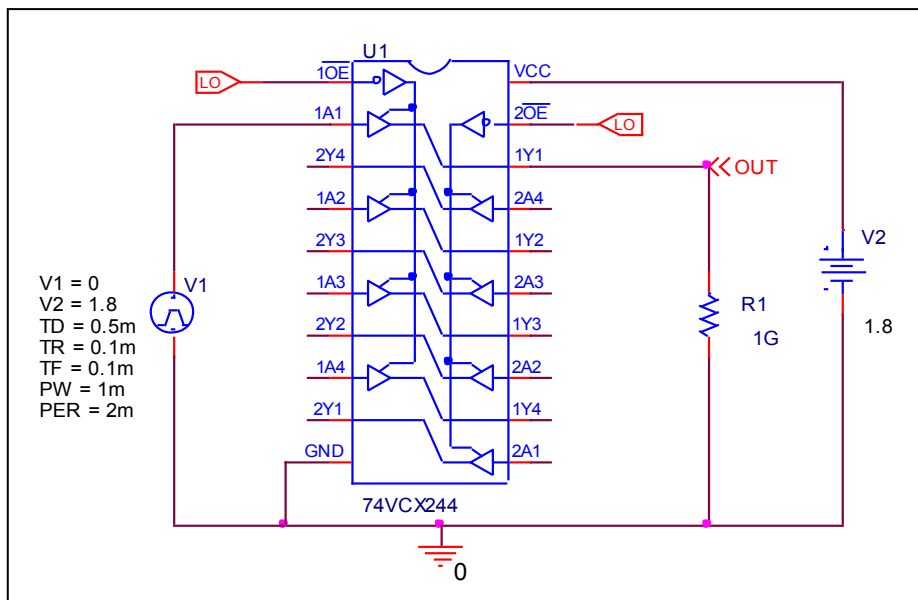
$V_{CC} = 2.5\text{ V}$	Measurement	Simulation	%Error
$V_{IH}\text{ (V)}$	1.6	1.6	0
$V_{IL}\text{ (V)}$	0.7	0.699080	-0.131

High Level and Low Level Input Voltage ($1.65\text{ V} \leq V_{CC} < 2.3\text{ V}$)

Circuit simulation result



Evaluation circuit

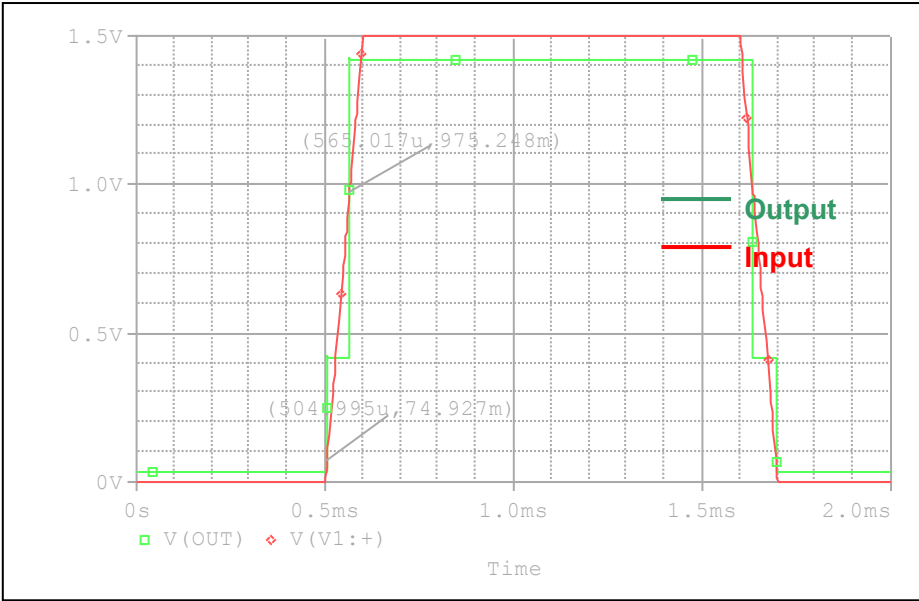


Comparison table

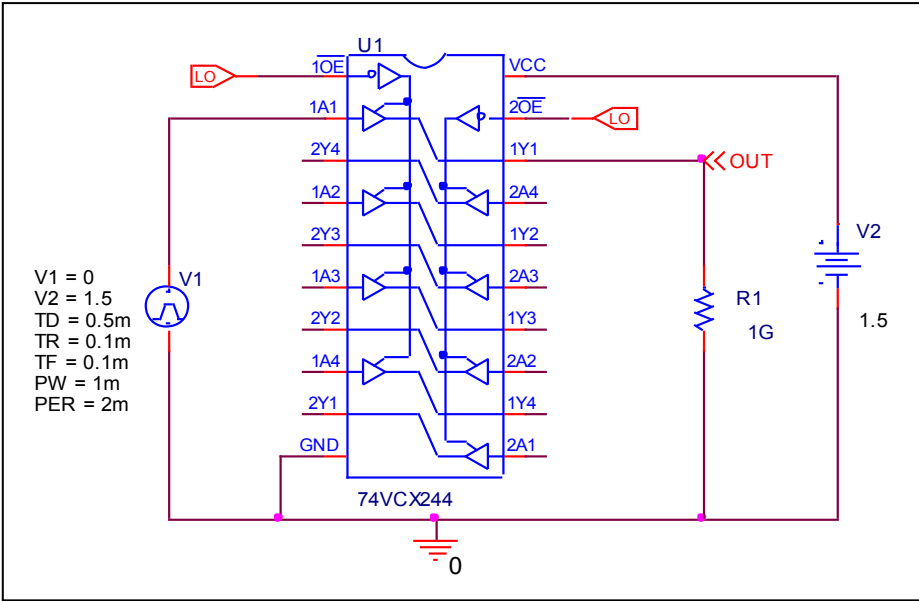
$V_{CC} = 1.8\text{ V}$	Measurement	Simulation	%Error
Min $V_{IH} = (V_{CC} \cdot 0.65)\text{ (V)}$	1.17	1.1702	0.017
Max $V_{IL} = (V_{CC} \cdot 0.2)\text{ (V)}$	0.36	0.358320	-0.467

High Level and Low Level Input Voltage ($1.4\text{ V} \leq V_{CC} < 1.65\text{ V}$)

Circuit simulation result



Evaluation circuit

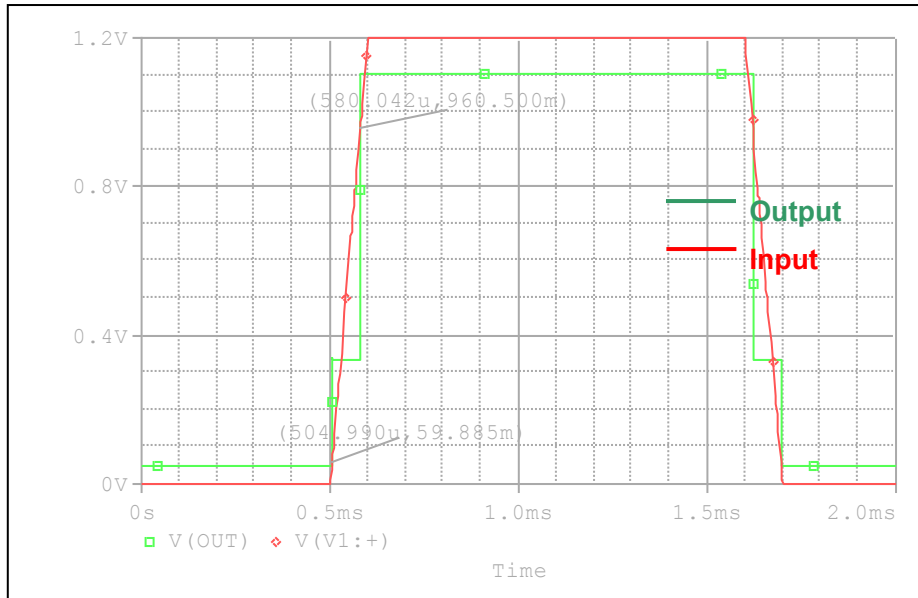


Comparison table

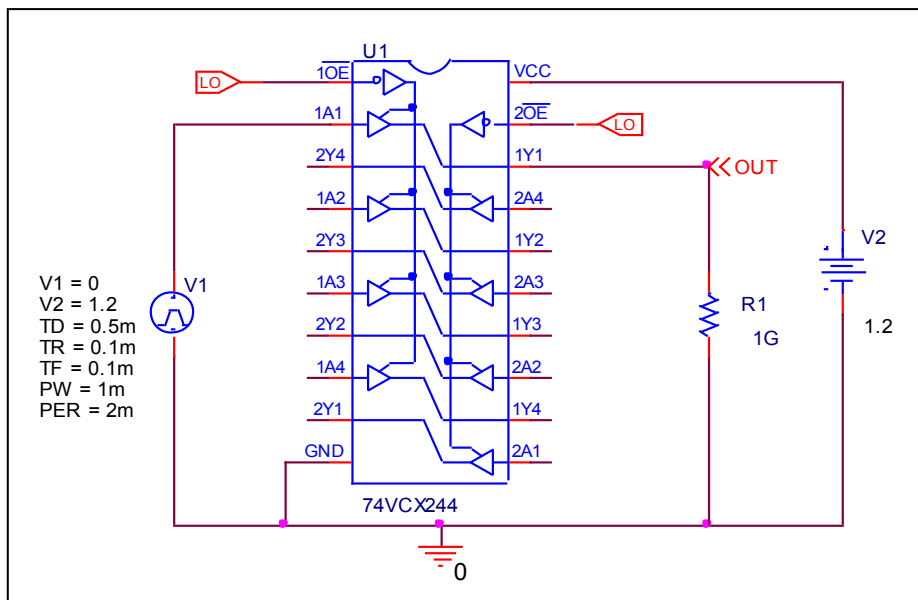
$V_{CC} = 1.5\text{ V}$	Measurement	Simulation	%Error
Min $V_{IH} = (V_{CC} \cdot 0.65)\text{ (V)}$	0.975	0.975248	0.025
Max $V_{IL} = (V_{CC} \cdot 0.05)\text{ (V)}$	0.075	0.074927	-0.097

High Level and Low Level Input Voltage ($1.2\text{ V} \leq V_{CC} < 1.4\text{ V}$)

Circuit simulation result



Evaluation circuit

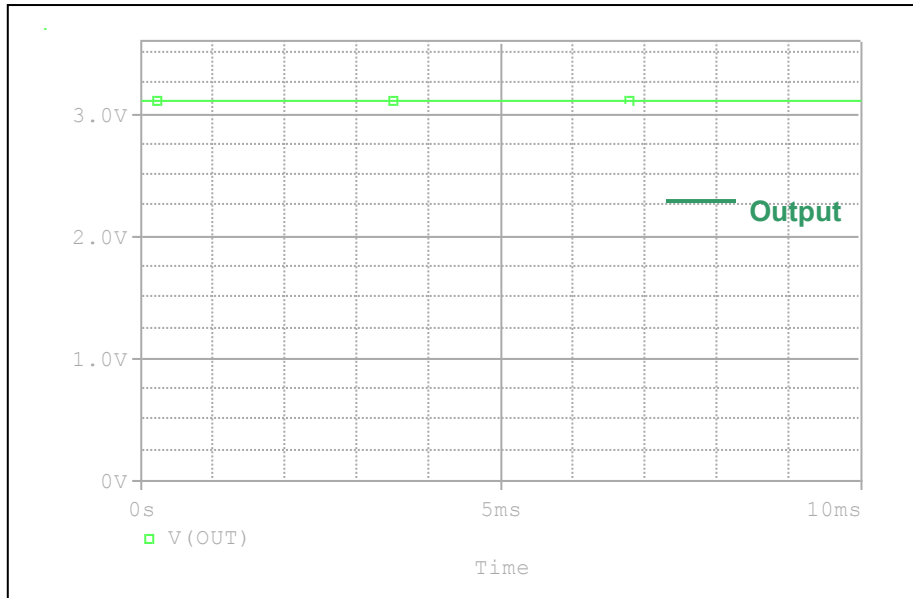


Comparison table

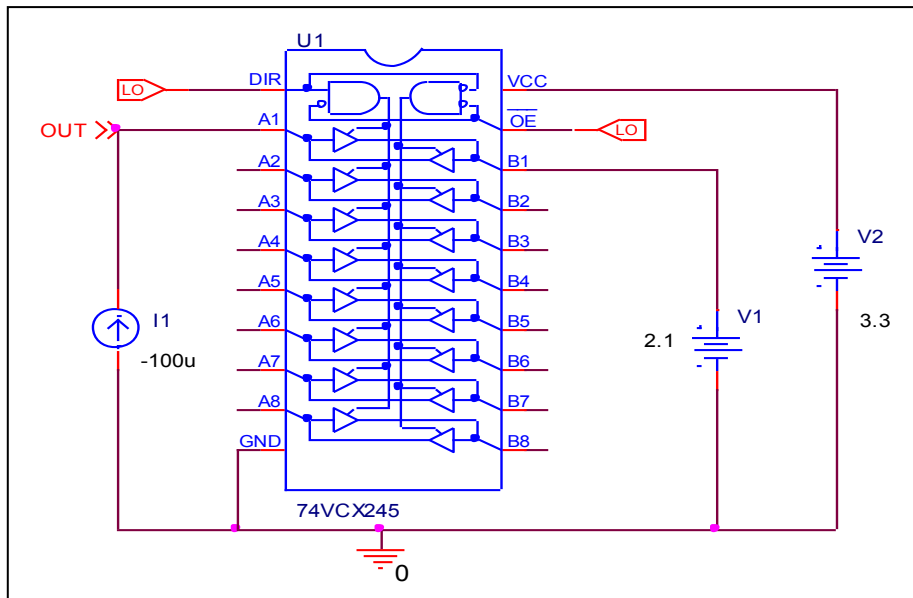
$V_{CC} = 1.2\text{ V}$	Measurement	Simulation	%Error
Min $V_{IH} = (V_{CC} \cdot 0.8)\text{ (V)}$	0.96	0.9605	0.052
Max $V_{IL} = (V_{CC} \cdot 0.05)\text{ (V)}$	0.06	0.059885	-0.192

High Level Output Voltage ($2.7\text{ V} < V_{CC} \leq 3.6\text{ V}$)

Circuit simulation result



Evaluation circuit

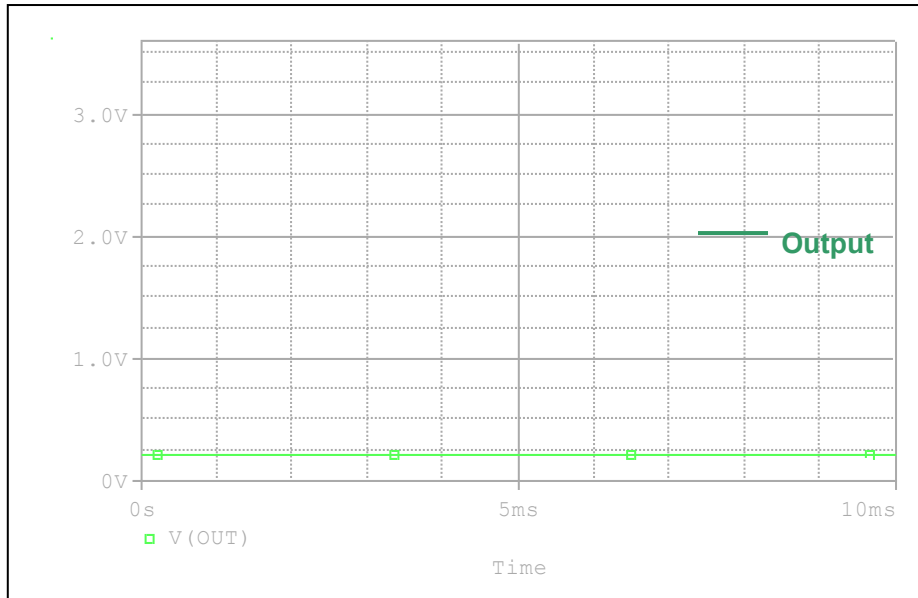


Comparison table

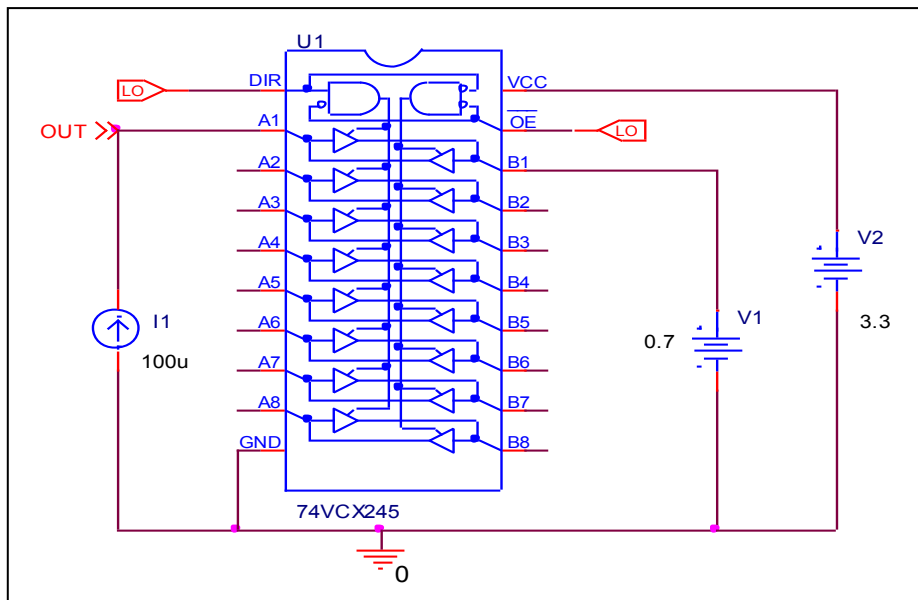
$V_{IN} = V_{IH}, V_{CC} = 3.3\text{ V}$	Measurement	Simulation	%Error
Min $V_{OH} = (V_{CC} - 0.2)\text{ V}$	3.1	3.1167	0.539

Low Level Output Voltage ($2.7\text{ V} < V_{CC} \leq 3.6\text{ V}$)

Circuit simulation result



Evaluation circuit

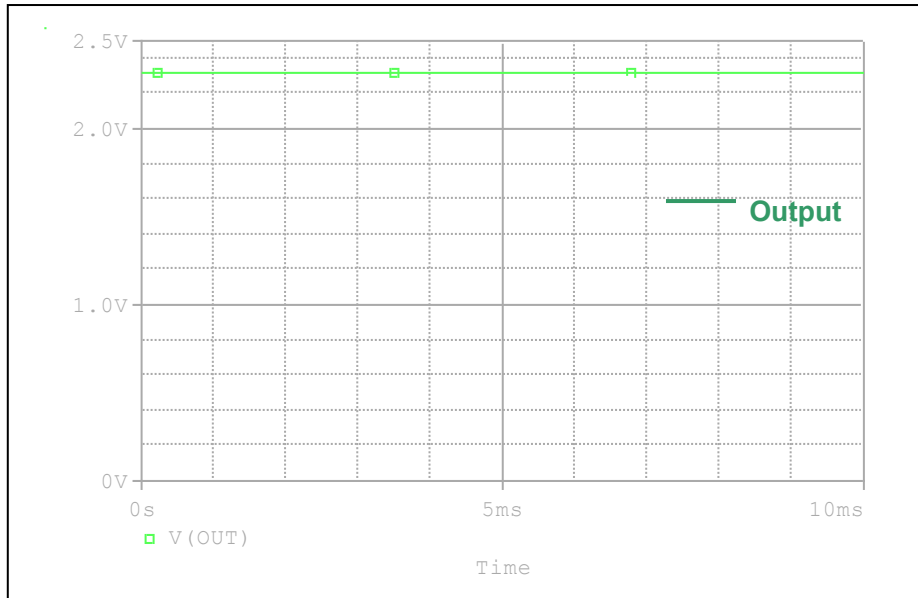


Comparison table

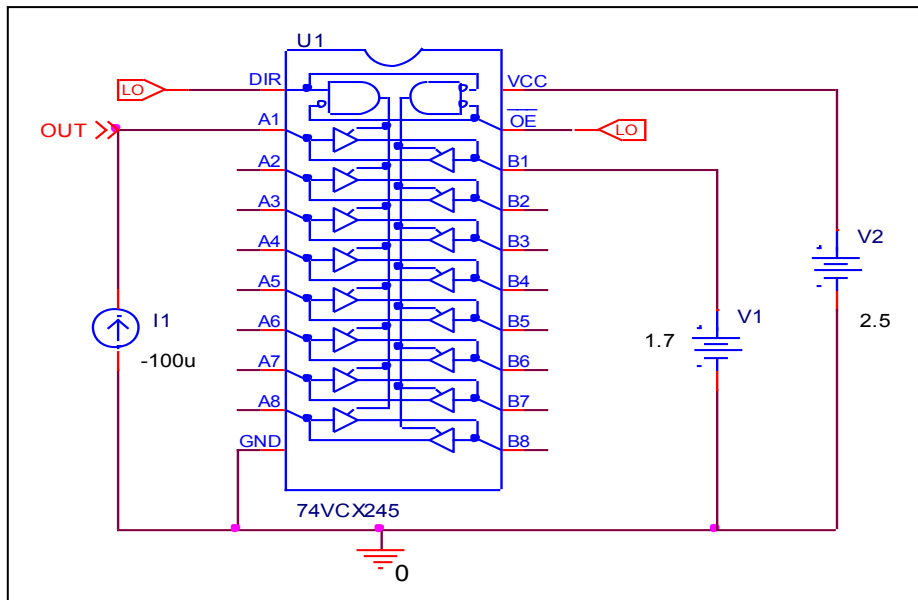
$V_{IN} = V_{IL}, V_{CC} = 3.3\text{ V}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0.2	0.207763	3.882

High Level Output Voltage ($2.3\text{ V} \leq V_{CC} \leq 2.7\text{ V}$)

Circuit simulation result



Evaluation circuit

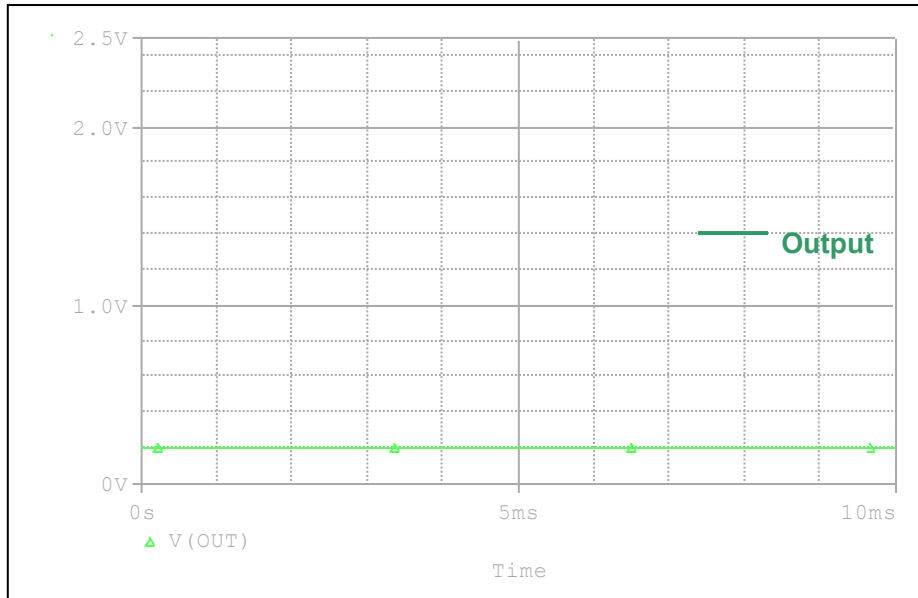


Comparison table

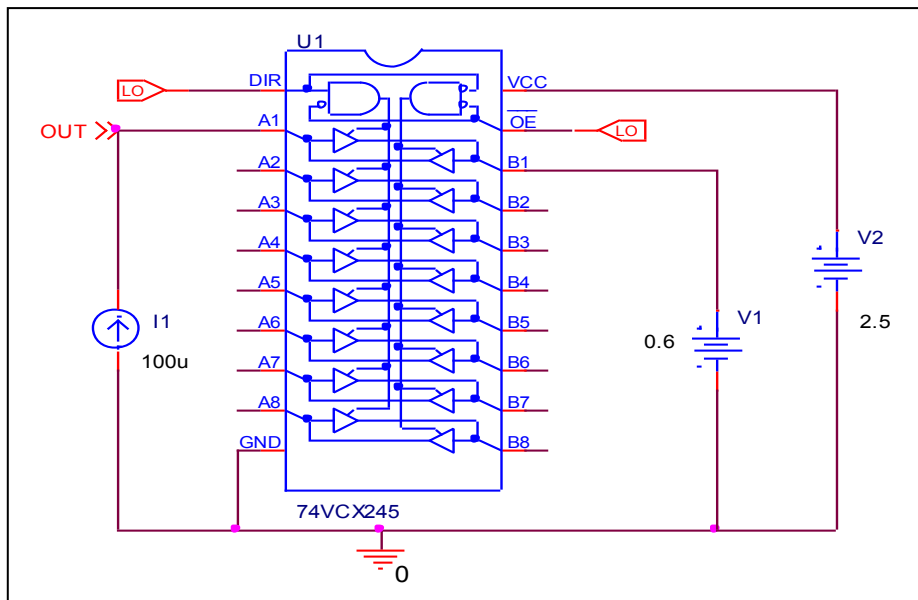
$V_{IN} = V_{IH}, V_{CC} = 2.5\text{ V}$	Measurement	Simulation	%Error
Min $V_{OH} = (V_{CC} - 0.2)\text{ V}$	2.3	2.3139	0.604

Low Level Output Voltage ($2.3\text{ V} \leq V_{CC} \leq 2.7\text{ V}$)

Circuit simulation result



Evaluation circuit

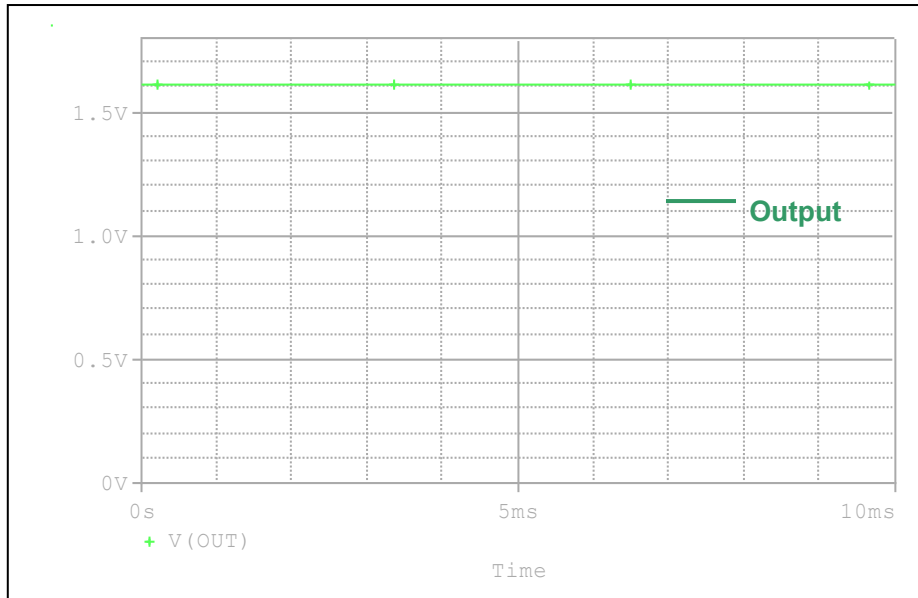


Comparison table

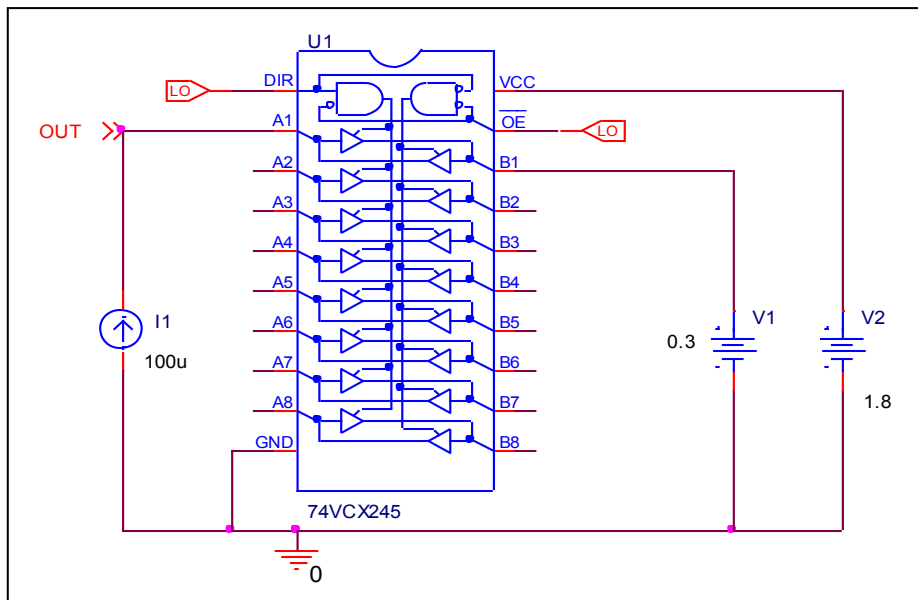
$V_{IN} = V_{IL}, V_{CC} = 2.5\text{ V}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0.2	0.202055	1.028

High Level Output Voltage ($1.65\text{ V} \leq V_{CC} < 2.3\text{ V}$)

Circuit simulation result



Evaluation circuit

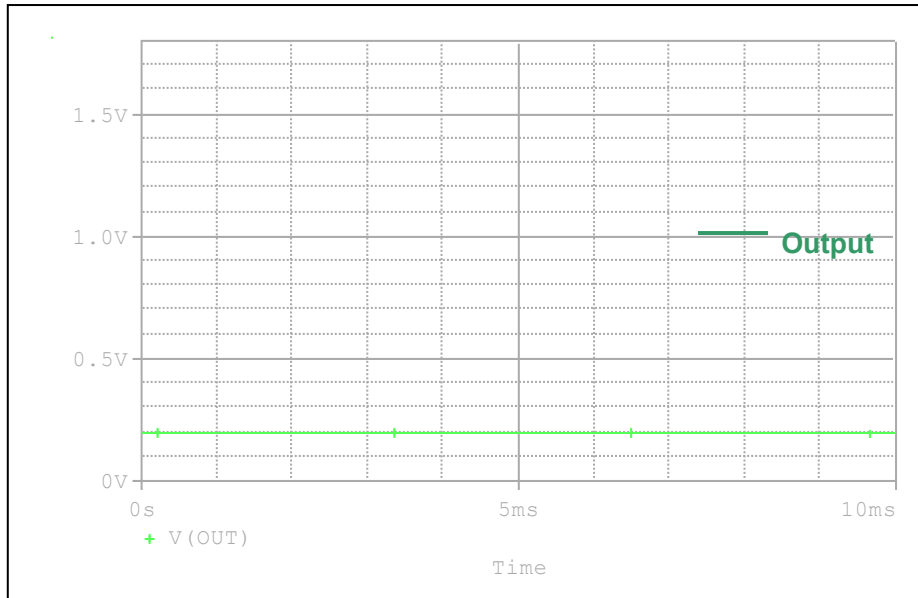


Comparison table

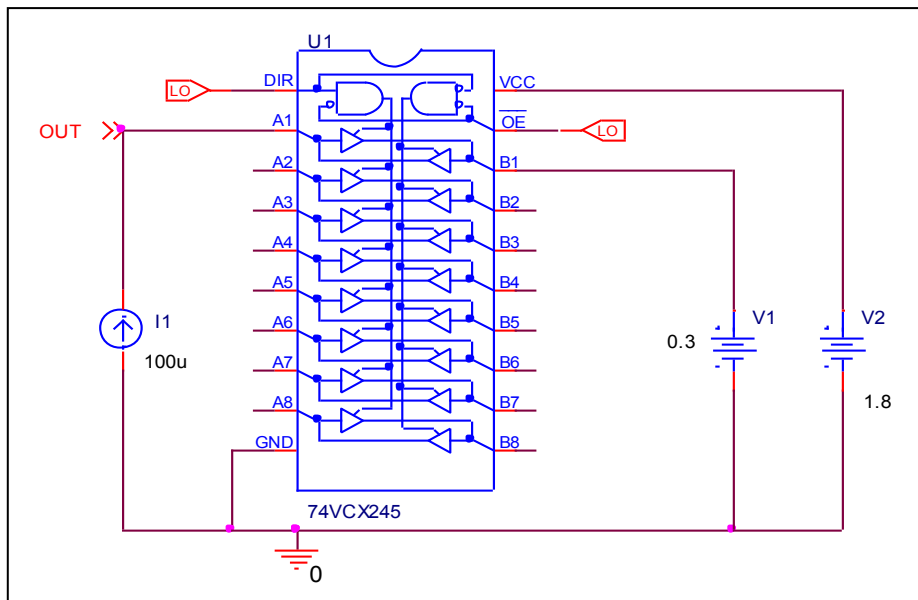
$V_{IN} = V_{IH}, V_{CC} = 1.8\text{ V}$	Measurement	Simulation	%Error
Min $V_{OH} = (V_{CC} - 0.2)\text{ V}$	1.6	1.6127	0.794

Low Level Output Voltage ($1.65\text{ V} \leq V_{CC} < 2.3\text{ V}$)

Circuit simulation result



Evaluation circuit

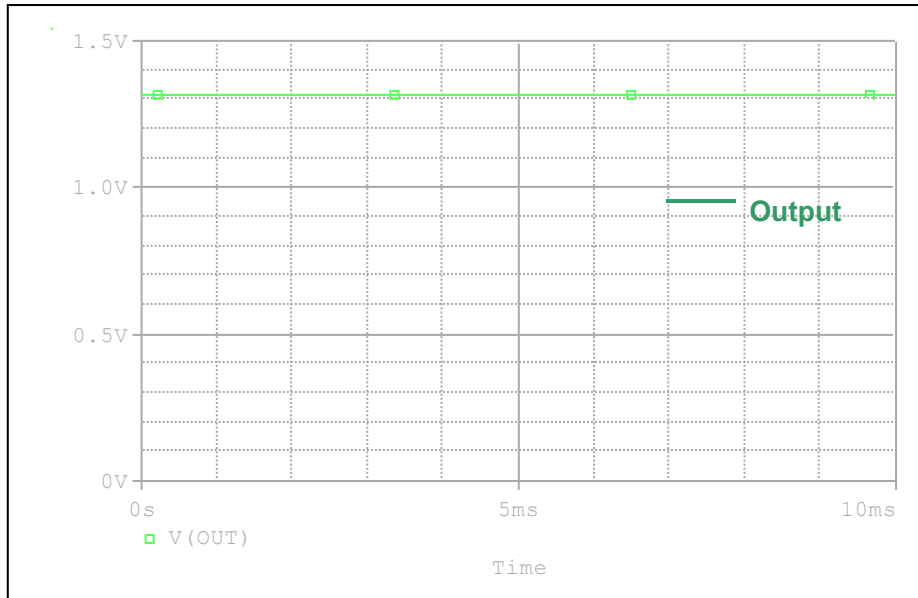


Comparison table

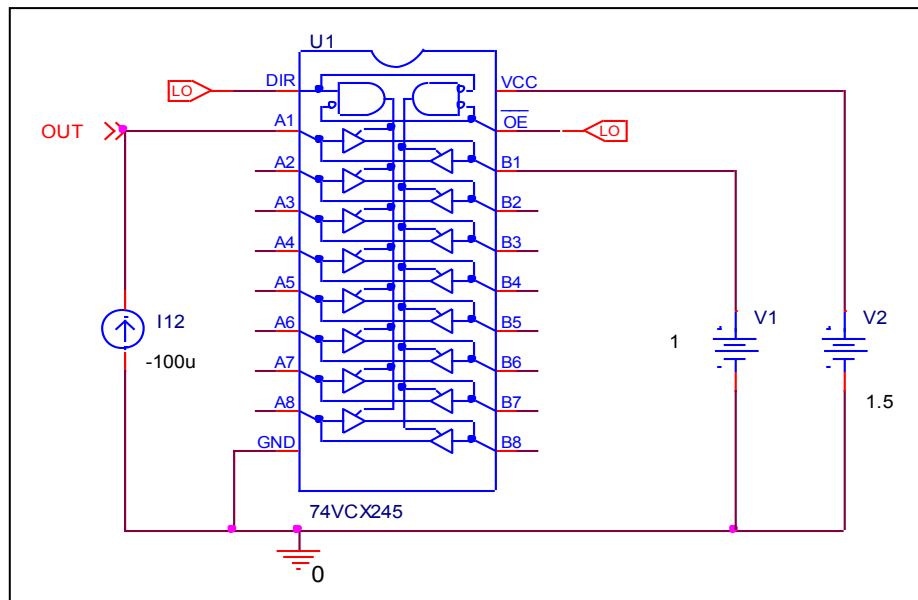
$V_{IN} = V_{IL}, V_{CC} = 1.8\text{ V}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0.2	0.198052	-0.974

High Level Output Voltage ($1.4\text{ V} \leq V_{CC} < 1.65\text{ V}$)

Circuit simulation result



Evaluation circuit

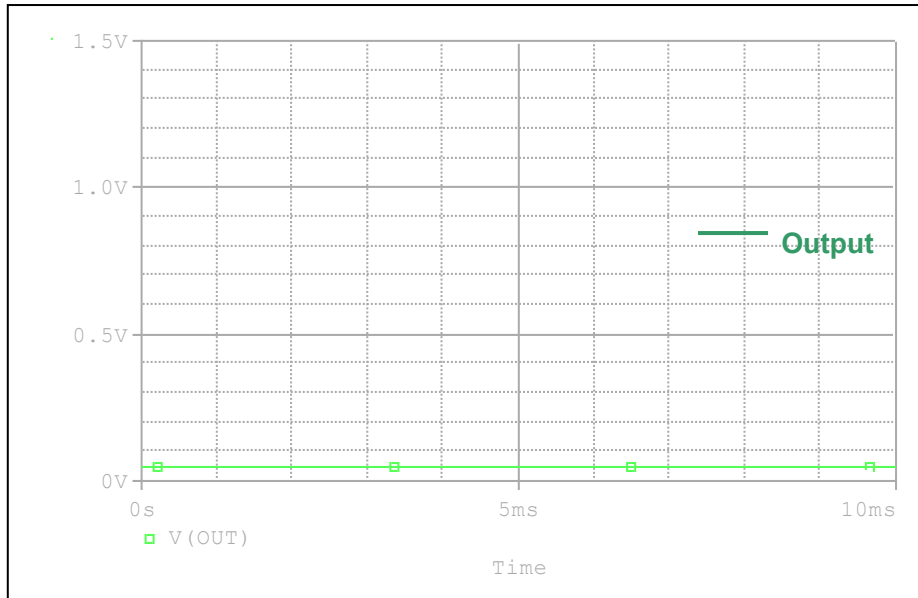


Comparison table

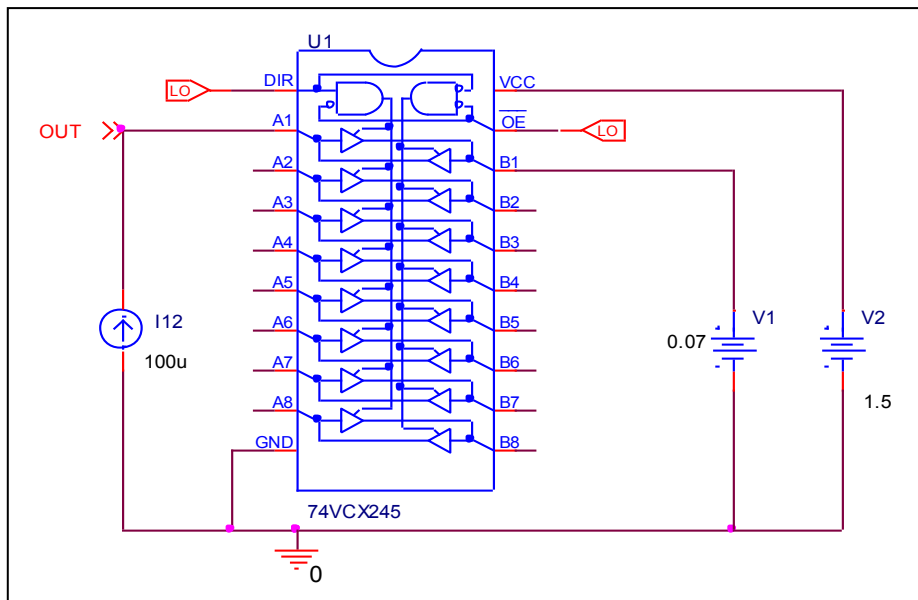
$V_{IN} = V_{IH}, V_{CC} = 1.5\text{ V}$	Measurement	Simulation	%Error
Min $V_{OH} = (V_{CC} - 0.2)\text{ V}$	1.3	1.3148	1.138

Low Level Output Voltage ($1.4\text{ V} \leq V_{CC} < 1.65\text{ V}$)

Circuit simulation result



Evaluation circuit

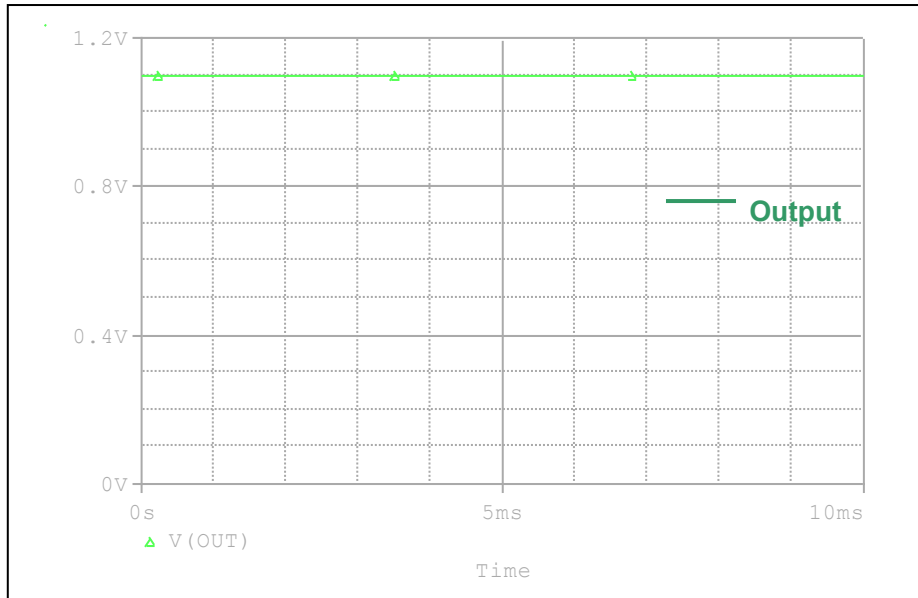


Comparison table

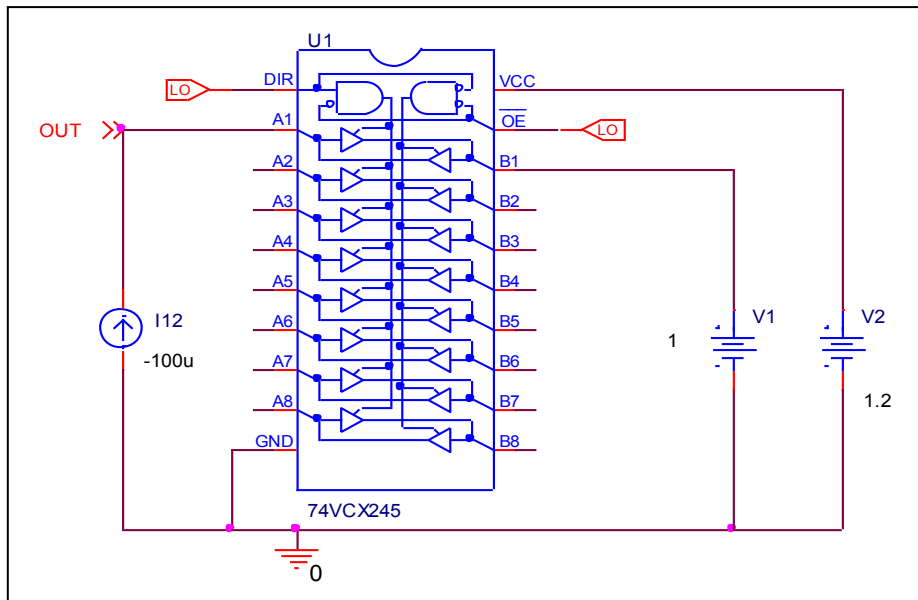
$V_{IN} = V_{IL}, V_{CC} = 1.5\text{ V}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0.05	0.047899	-4.202

High Level Output Voltage ($1.2\text{ V} \leq V_{CC} < 1.4\text{ V}$)

Circuit simulation result



Evaluation circuit

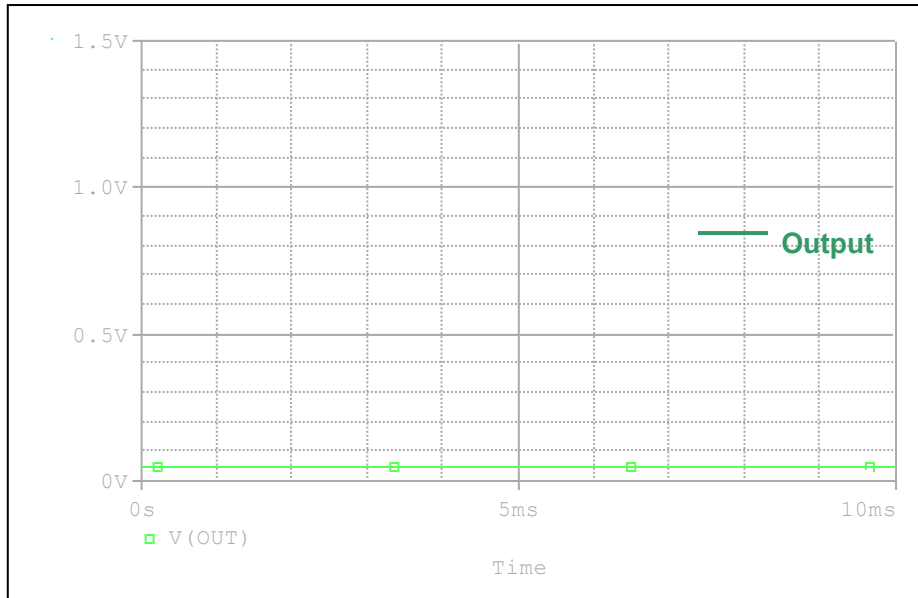


Comparison table

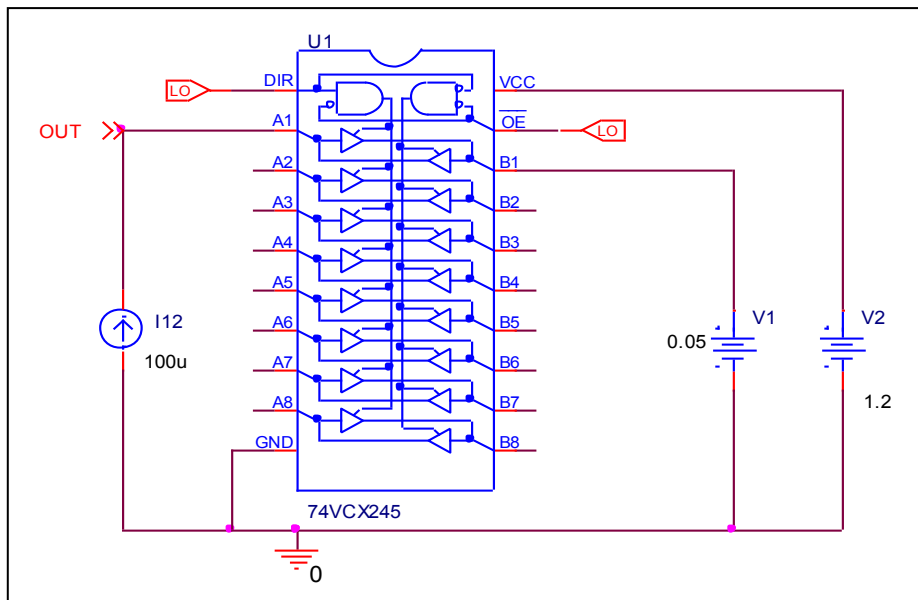
$V_{IN} = V_{IH}, V_{CC} = 1.2\text{ V}$	Measurement	Simulation	%Error
Min $V_{OH} = (V_{CC} - 0.1)\text{ V}$	1.1	1.1002	0.018

Low Level Output Voltage ($1.2\text{ V} \leq V_{CC} < 1.4\text{ V}$)

Circuit simulation result



Evaluation circuit

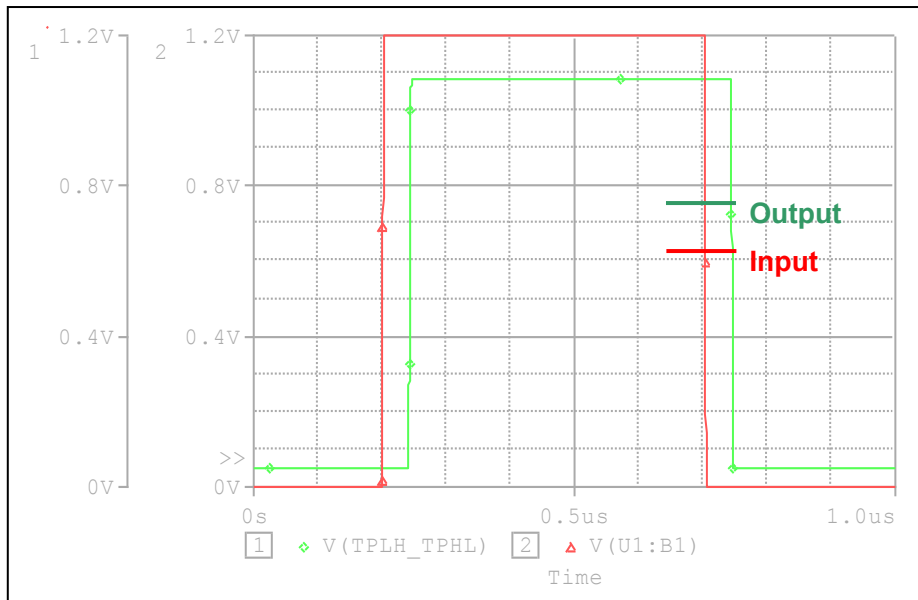


Comparison table

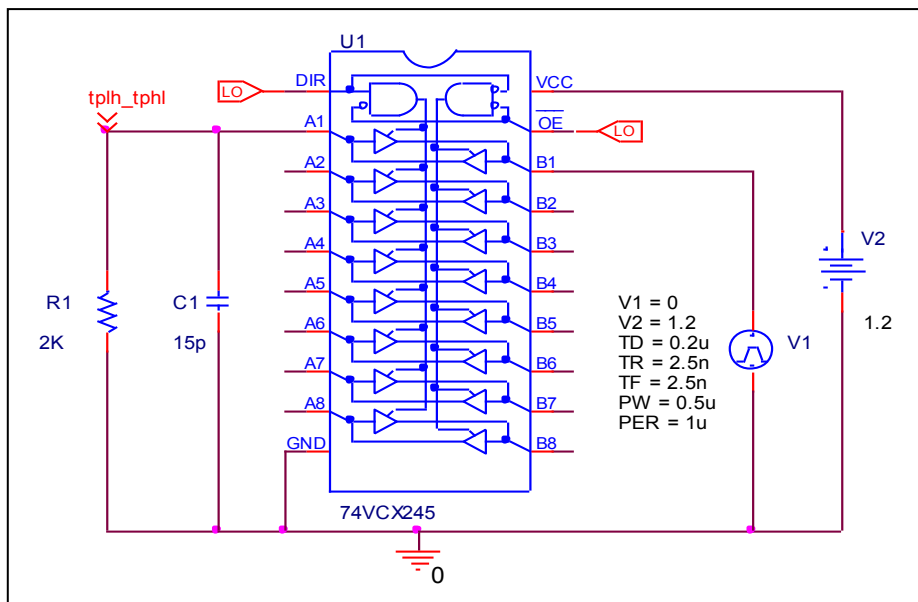
$V_{IN} = V_{IL}, V_{CC} = 1.2\text{ V}$	Measurement	Simulation	%Error
$V_{OL}\text{ (V)}$	0.05	0.048448	-3.104

Propagation Delay Time ($V_{CC} = 1.2\text{ V}$)

Circuit simulation result



Evaluation circuit

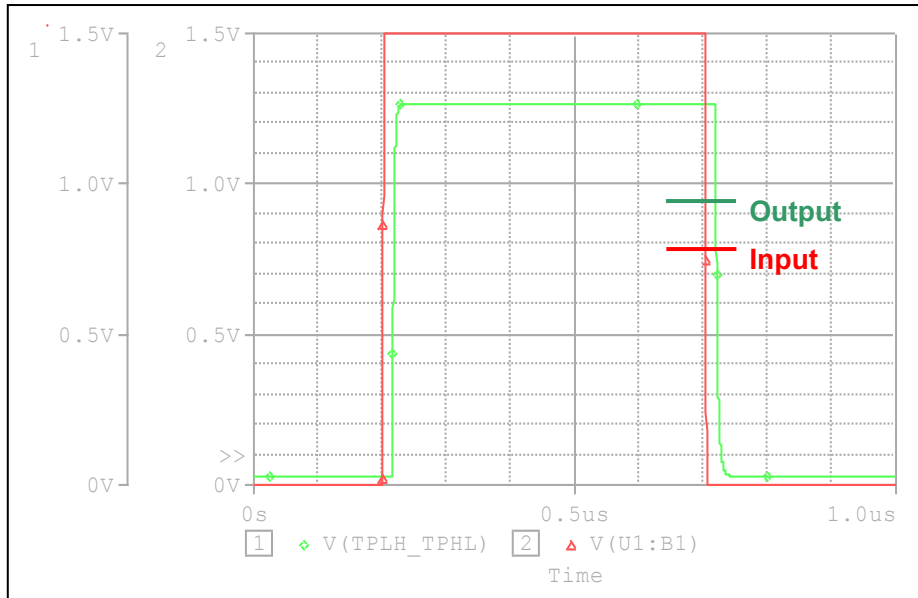


Comparison table $C_L = 15\text{ pF}$, $R_L = 2\text{ K}\Omega$

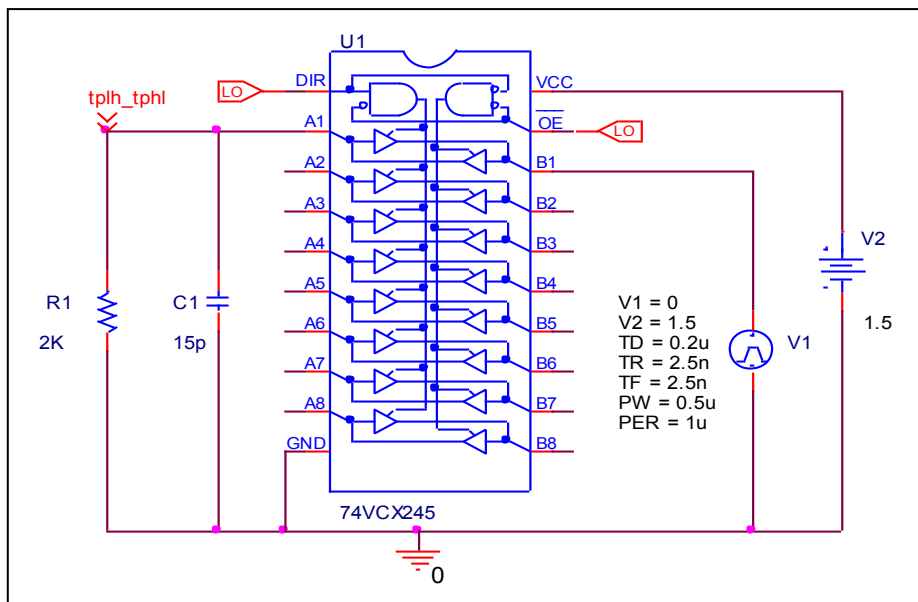
$V_{CC} = 1.2\text{ V}$, $t_r=t_f = 2\text{ ns}$	Measurement	Simulation	%Error
$t_{pLH}\text{ (ns)}$	42	41.775	-0.536
$t_{pHL}\text{ (ns)}$	42	41.761	-0.569

Propagation Delay Time ($V_{CC} = 1.5\text{ V}$)

Circuit simulation result



Evaluation circuit

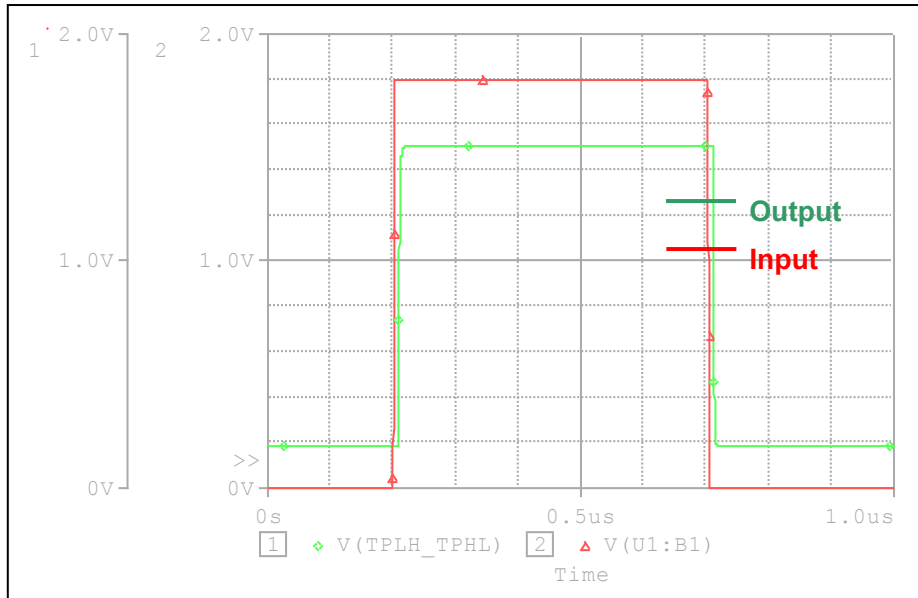


Comparison table $C_L = 15\text{ pF}$, $R_L = 2\text{ K}\Omega$

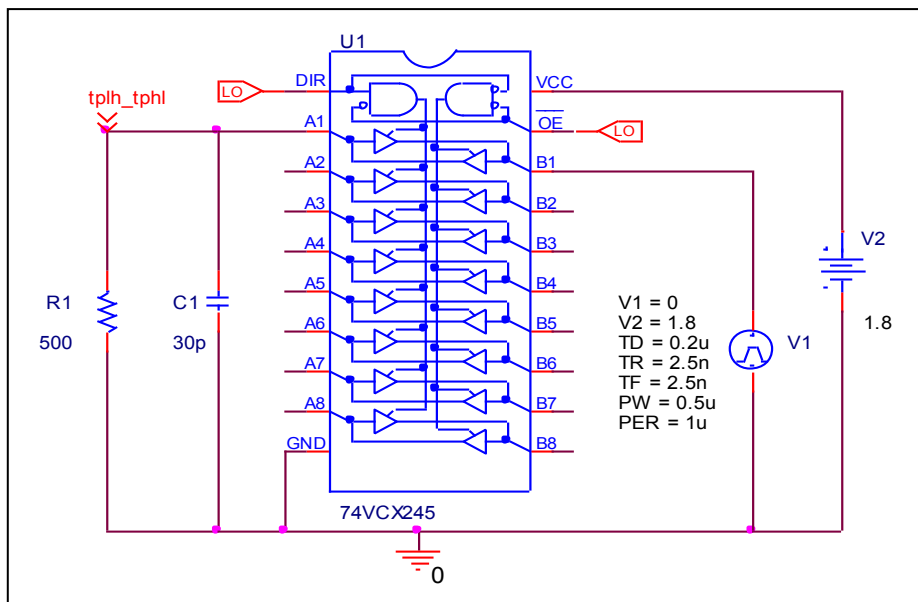
$V_{CC} = 1.5\text{ V}$, $t_r=t_f = 2\text{ ns}$	Measurement	Simulation	%Error
$t_{pLH}\text{ (ns)}$	16.8	16.430	-2.202
$t_{pHL}\text{ (ns)}$	16.8	16.628	-1.024

Propagation Delay Time ($V_{CC} = 1.8 \text{ V}$)

Circuit simulation result



Evaluation circuit

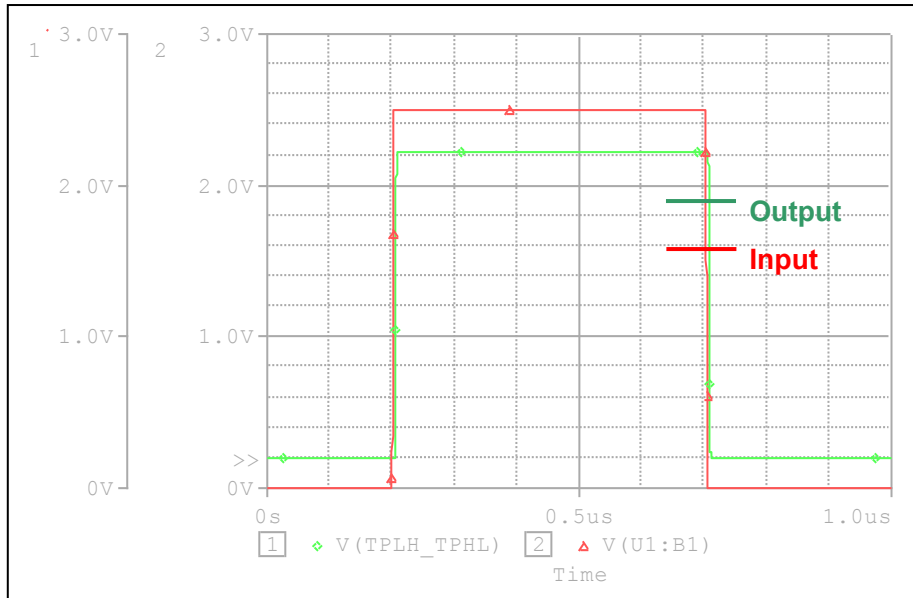


Comparison table $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$

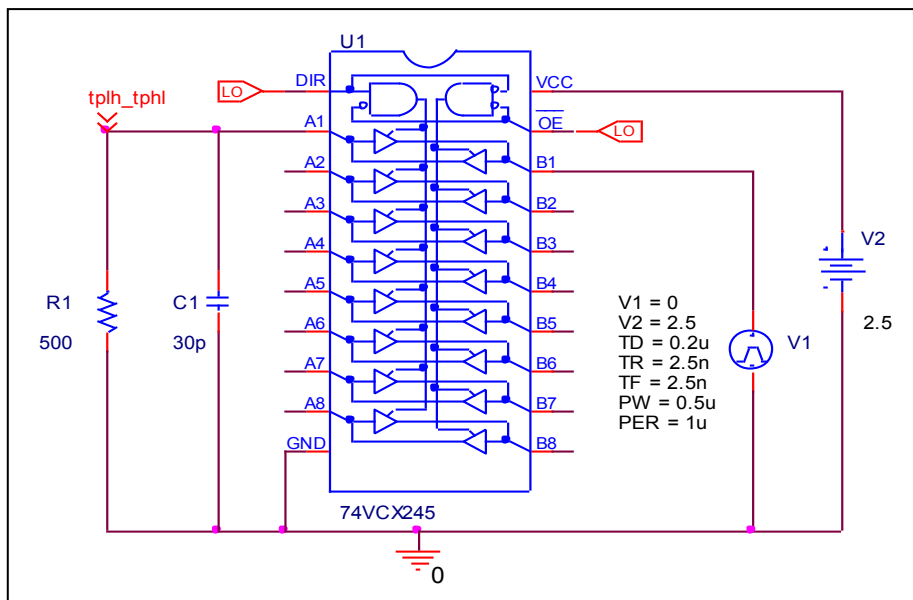
$V_{CC} = 1.8 \text{ V}$, $t_r=t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{pLH} \text{ (ns)}$	8.4	8.2719	-1.525
$t_{pHL} \text{ (ns)}$	8.4	8.3228	-0.919

Propagation Delay Time ($V_{CC} = 2.5\text{ V}$)

Circuit simulation result



Evaluation circuit

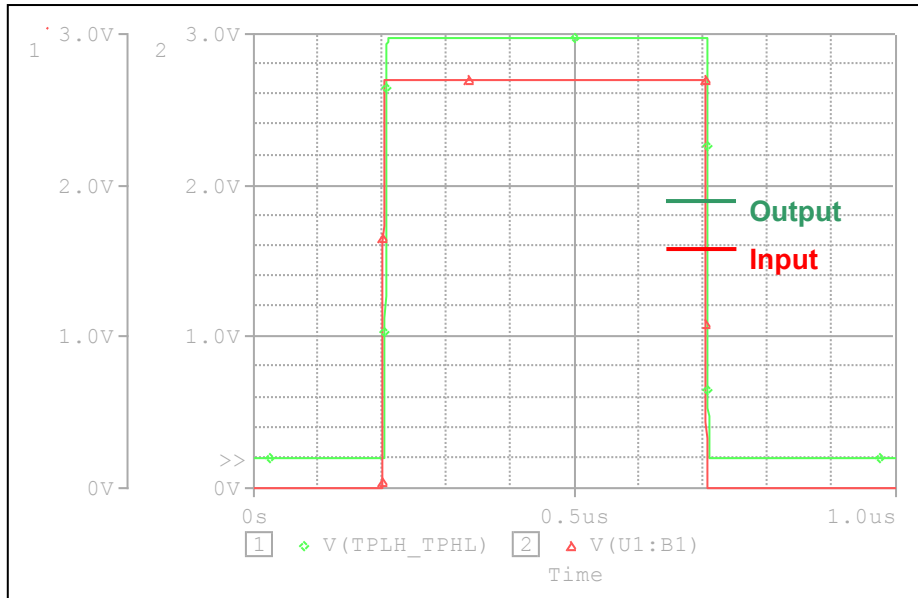


Comparison table $C_L = 30\text{ pF}$, $R_L = 500\ \Omega$

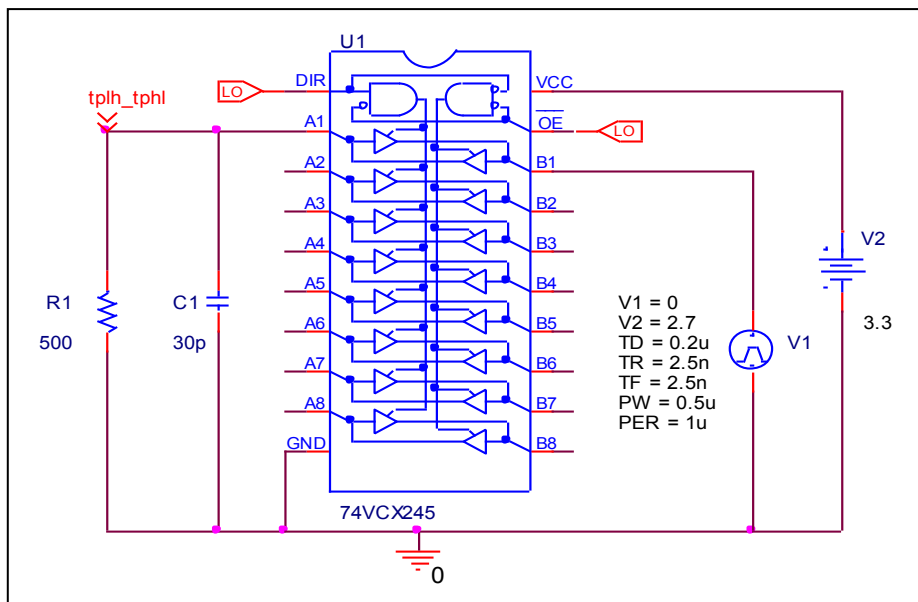
$V_{CC} = 2.5\text{ V}$, $t_r=t_f = 2\text{ ns}$	Measurement	Simulation	%Error
$t_{pLH}\text{ (ns)}$	4.2	4.1483	-1.231
$t_{pHL}\text{ (ns)}$	4.2	4.2043	0.102

Propagation Delay Time ($V_{CC} = 3.3$)

Circuit simulation result



Evaluation circuit

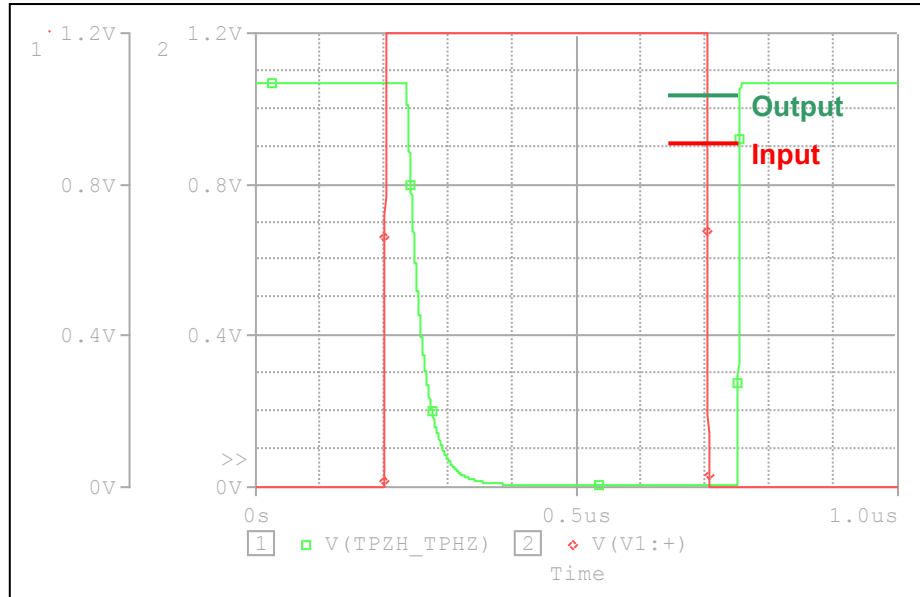


Comparison table $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$

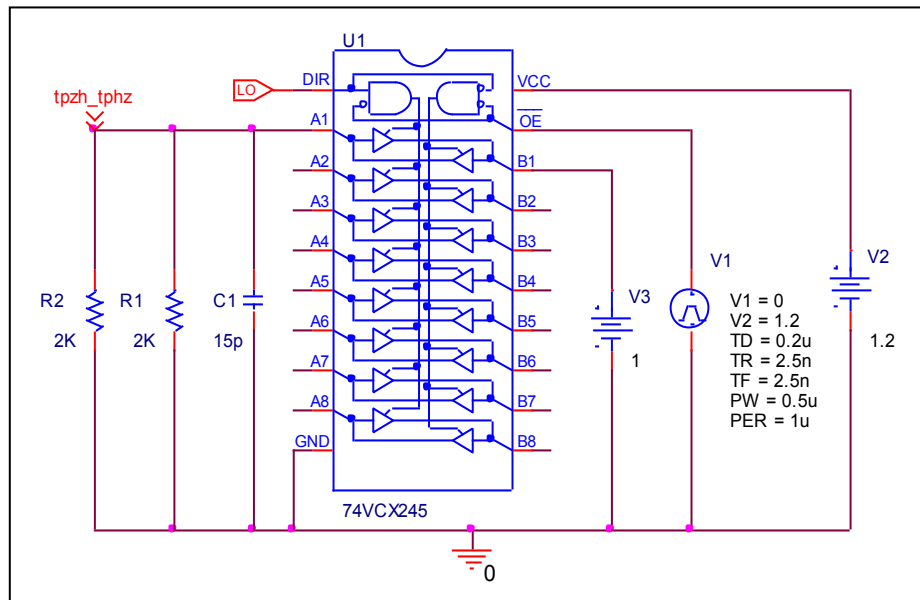
$V_{CC} = 3.3 \text{ V}$, $t_r=t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{pLH} \text{ (ns)}$	3.5	3.4489	-1.460
$t_{pHL} \text{ (ns)}$	3.5	3.4608	-1.120

Output enable time(t_{PZH}) and Output disable time(t_{PHZ}) ($V_{CC} = 1.2$)

Circuit simulation result



Evaluation circuit

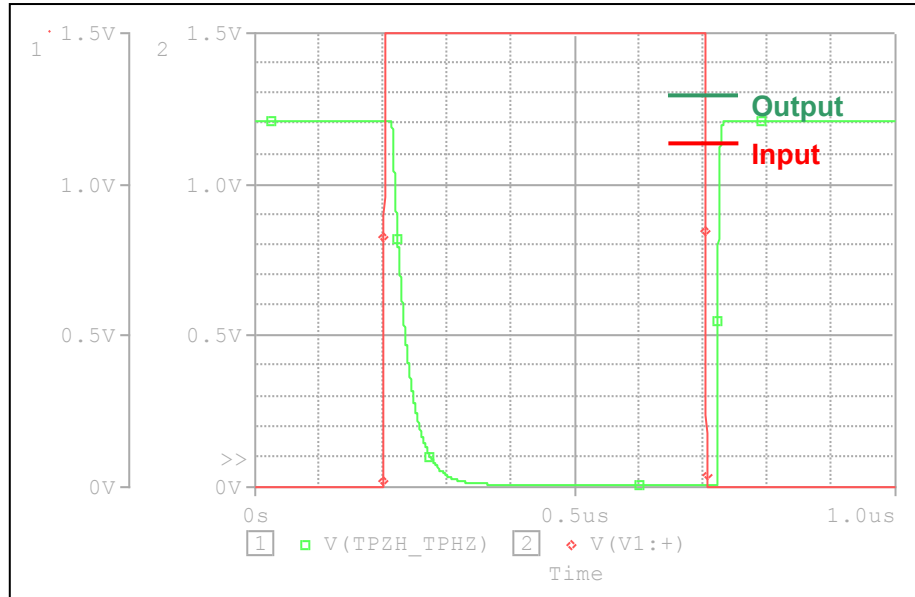


Comparison table $C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$

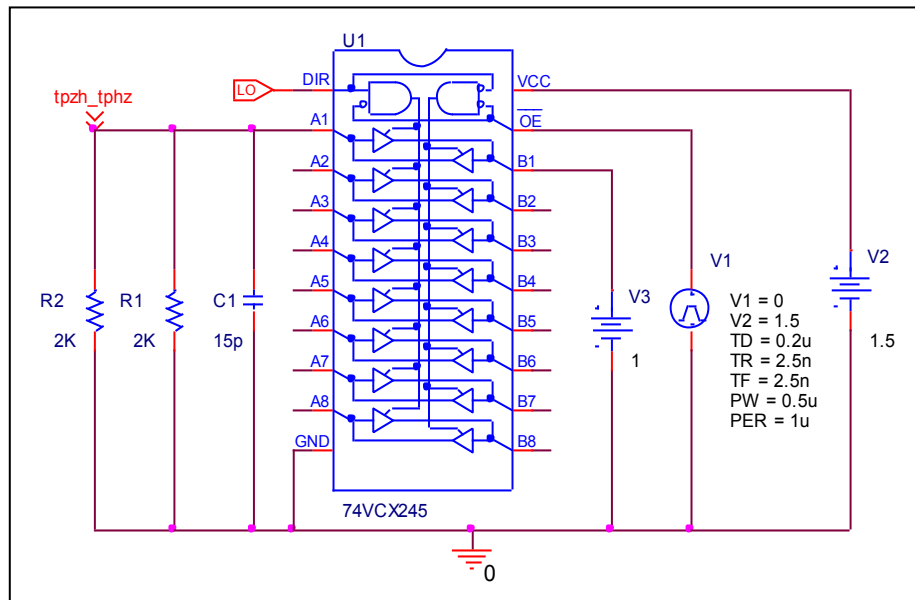
V_{CC} =1.2 V, t_r=t_f = 2 ns	Measurement	Simulation	%Error
t_{PHZ} (ns)	36	35.665	-0.931
t_{pZH} (ns)	49	48.407	-1.210

Output enable time(t_{pZH}) and Output disable time(t_{pHZ}) ($V_{CC} = 1.5$)

Circuit simulation result



Evaluation circuit

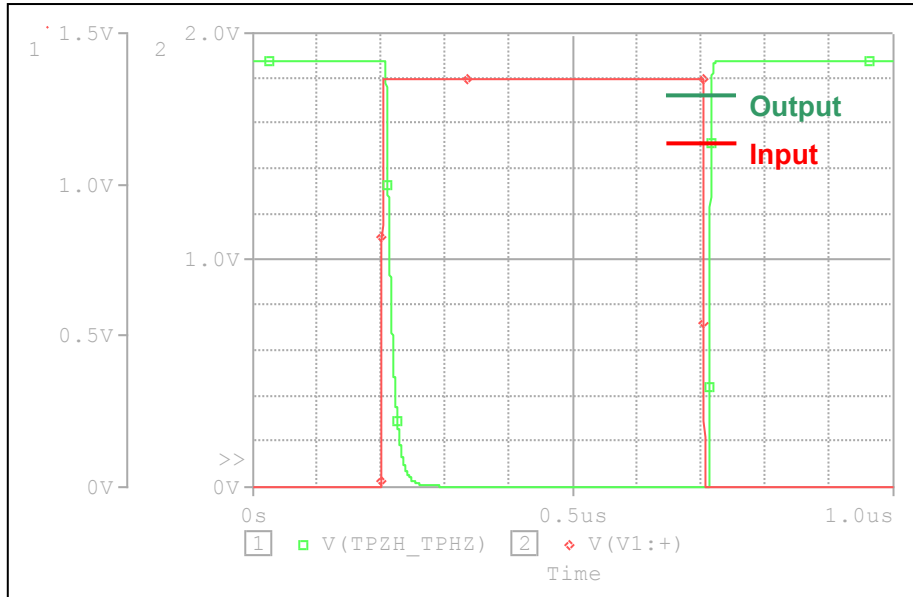


Comparison table $C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$

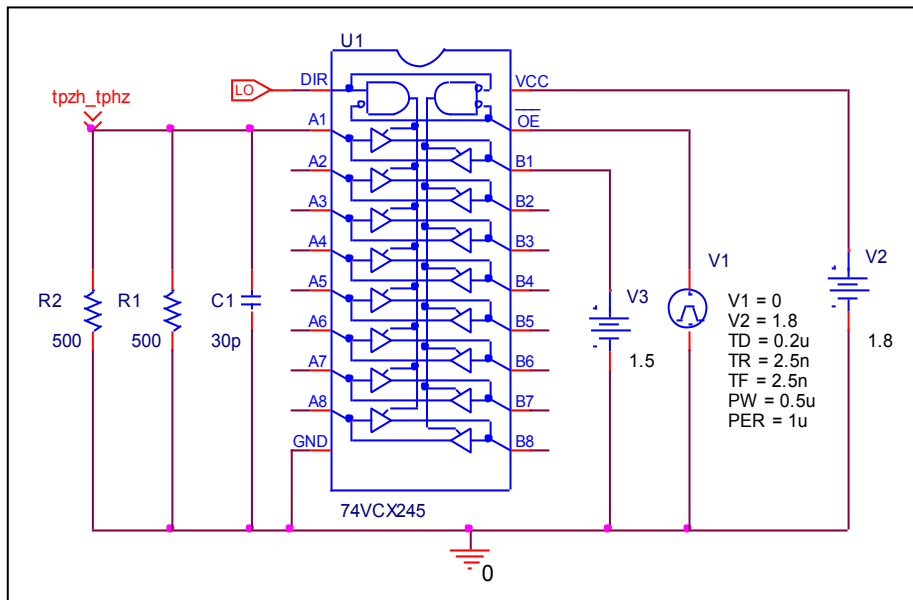
$V_{CC} = 1.5 \text{ V}$, $t_r = t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{pHZ} \text{ (ns)}$	14.4	14.343	-0.396
$t_{pZH} \text{ (ns)}$	19.6	19.422	-0.908

Output enable time(t_{pZH}) and Output disable time(t_{pHZ}) ($V_{CC} = 1.8$)

Circuit simulation result



Evaluation circuit

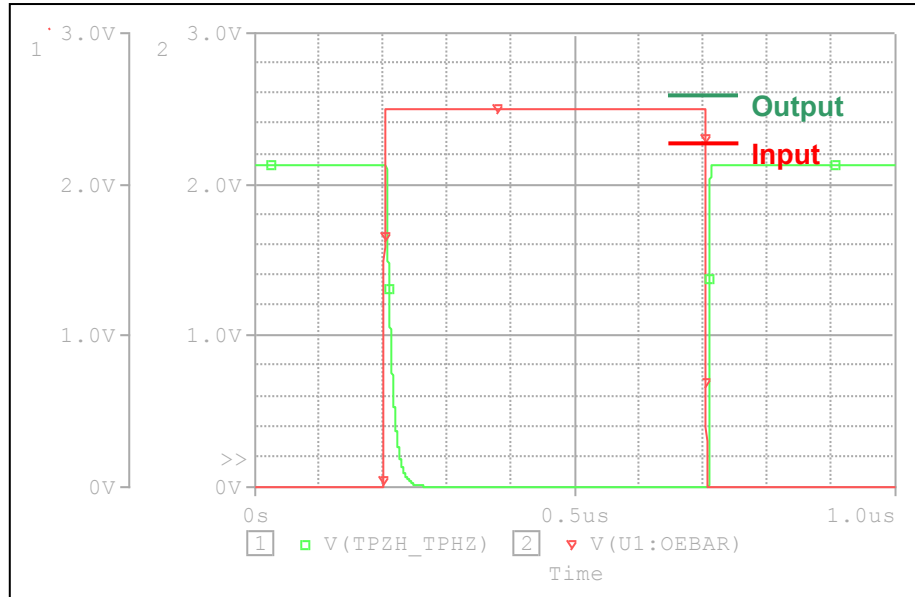


Comparison table $C_L = 30\text{ pF}$, $R_L = 500\ \Omega$

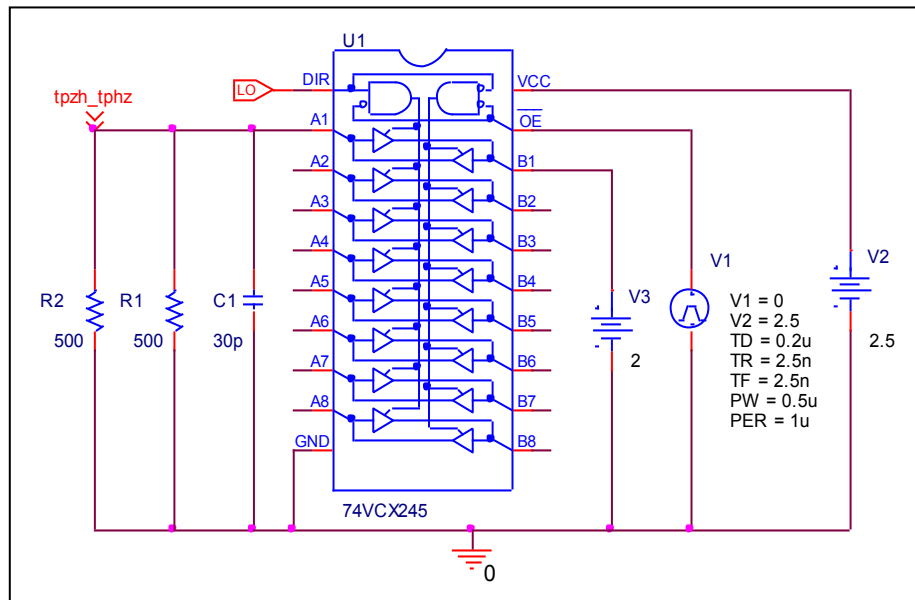
$V_{CC} = 1.8\text{ V}$, $t_r = t_f = 2\text{ ns}$	Measurement	Simulation	%Error
$t_{pHZ}\text{ (ns)}$	7.2	7.1372	-0.872
$t_{pZH}\text{ (ns)}$	9.8	9.728	-0.735

Output enable time(t_{pZH}) and Output disable time(t_{pHZ}) ($V_{CC} = 2.5$)

Circuit simulation result



Evaluation circuit

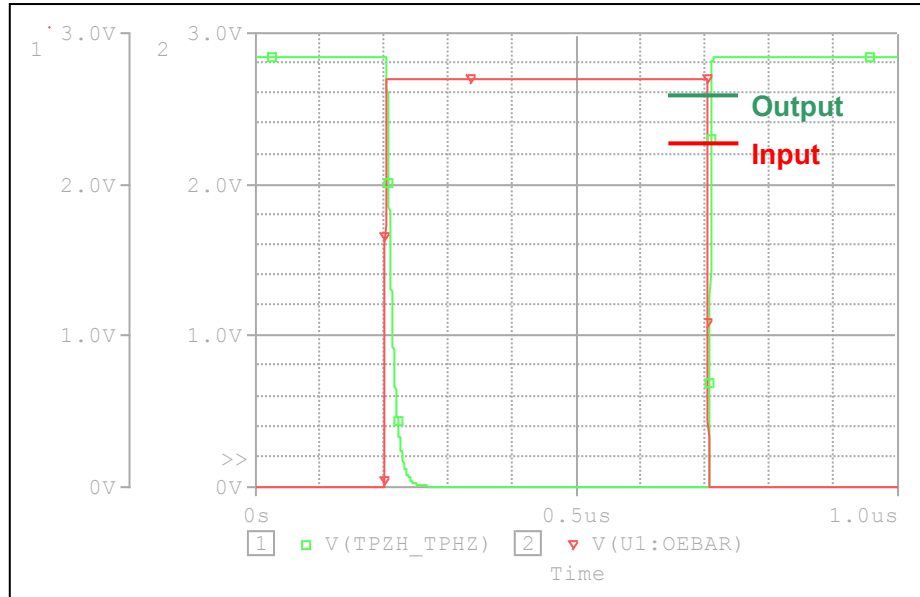


Comparison table $C_L = 30$ pF, $R_L = 500$ Ω

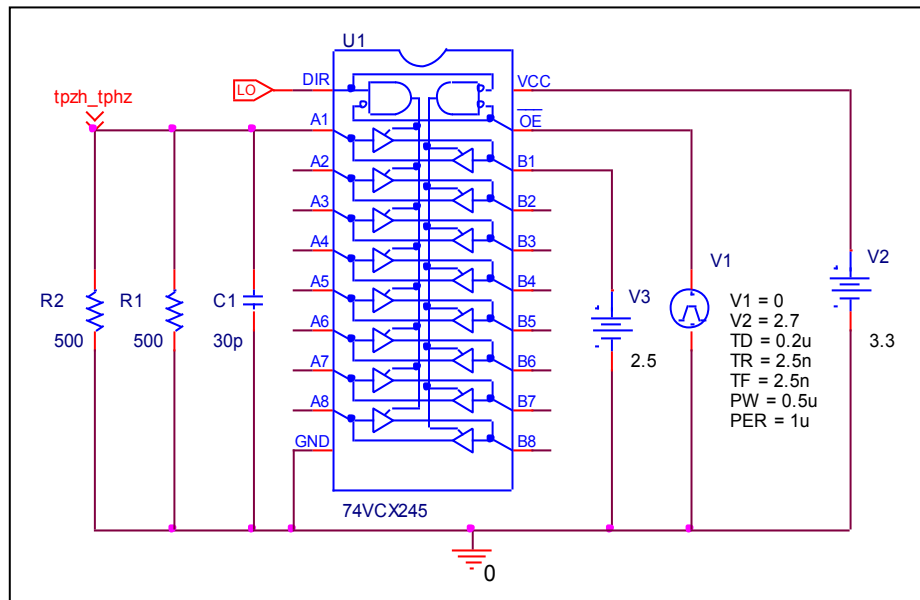
$V_{CC} = 2.5$ V, $t_r = t_f = 2$ ns	Measurement	Simulation	%Error
t_{pHZ} (ns)	4.0	4.0101	0.253
t_{pZH} (ns)	5.6	5.5637	-0.648

Output enable time(t_{pZH}) and Output disable time(t_{pHZ}) ($V_{CC} = 3.3$)

Circuit simulation result



Evaluation circuit

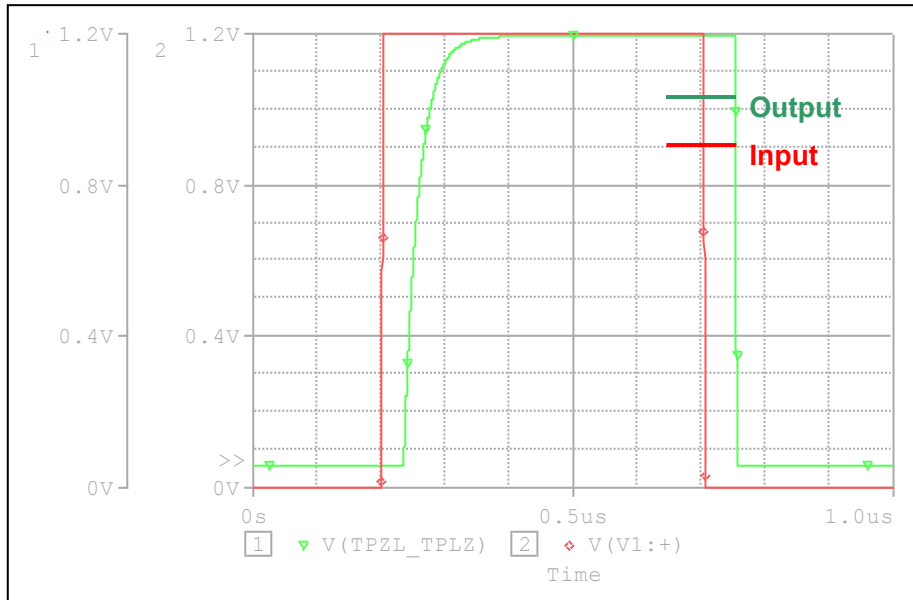


Comparison table $C_L = 30$ pF, $R_L = 500$ Ω

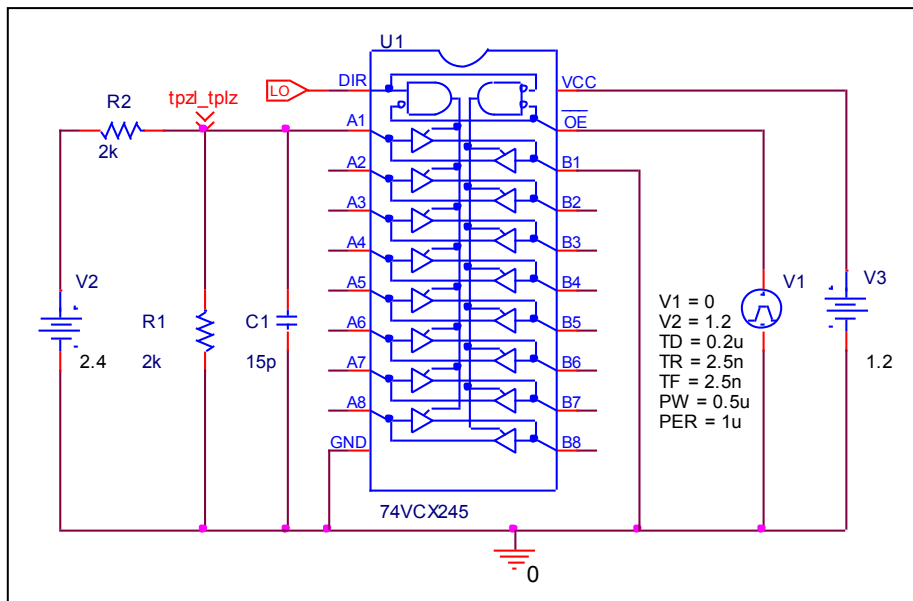
$V_{CC} = 3.3$ V, $t_r=t_f = 2$ ns	Measurement	Simulation	%Error
t_{PHZ} (ns)	3.6	3.5127	-2.425
t_{pZH} (ns)	4.5	4.3381	-3.598

Output enable time (t_{pZL}) and Output disable time (t_{PLZ}) ($V_{CC} = 1.2$)

Circuit simulation result



Evaluation circuit

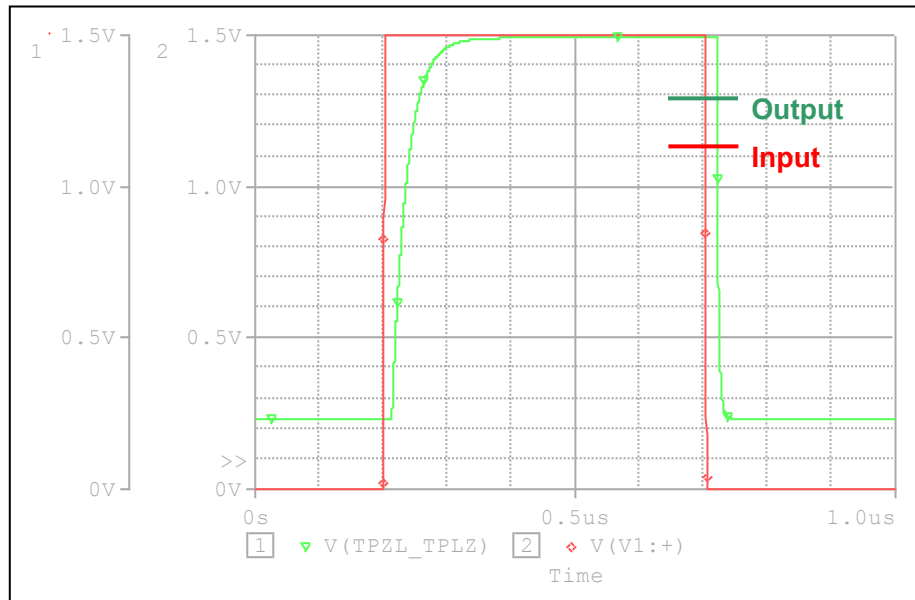


Comparison table $C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$

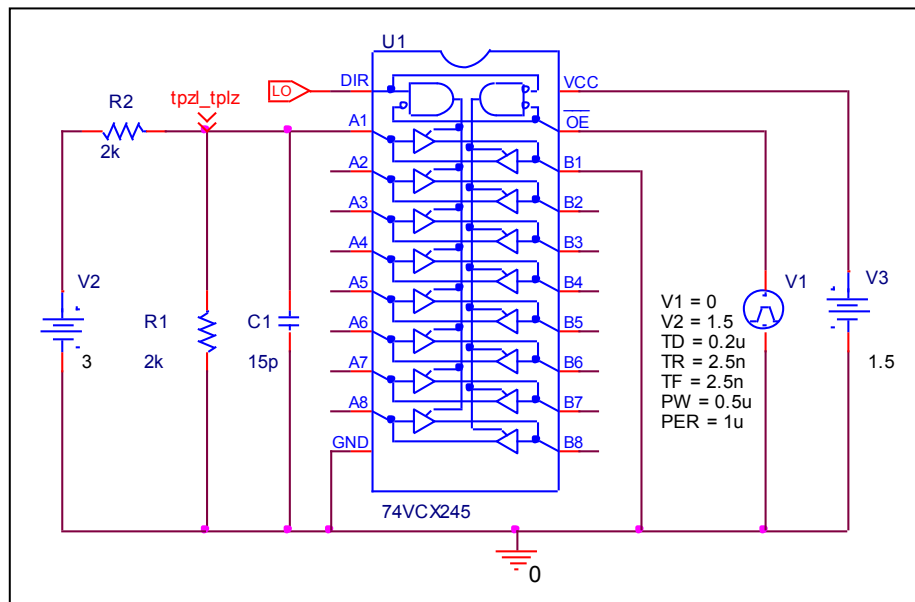
$V_{CC} = 1.2 \text{ V}$, $t_r = t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{PLZ} \text{ (ns)}$	36	35.485	-1.431
$t_{pZL} \text{ (ns)}$	49	48.771	-0.467

Output enable time (t_{PZL}) and Output disable time (t_{PLZ}) ($V_{CC} = 1.5$)

Circuit simulation result



Evaluation circuit

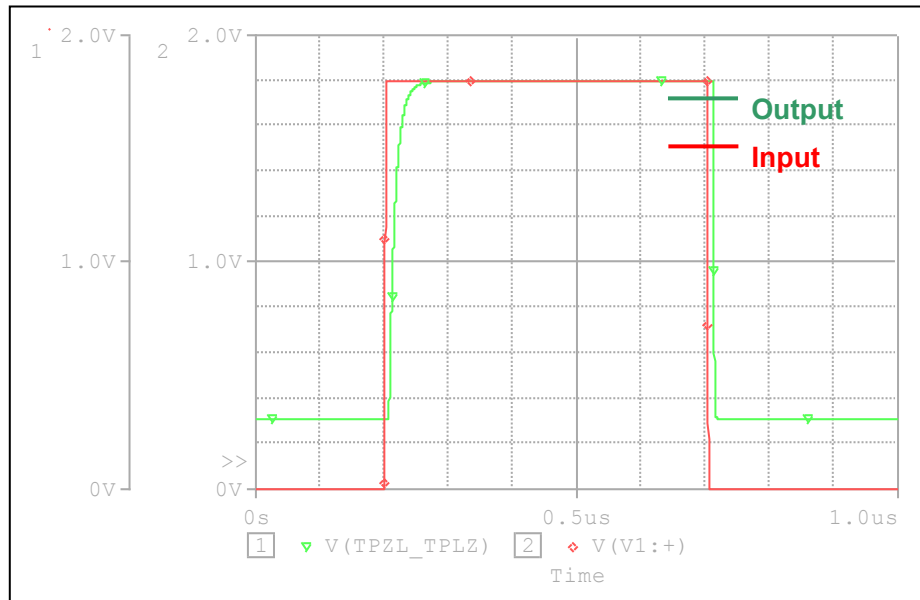


Comparison table $C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$

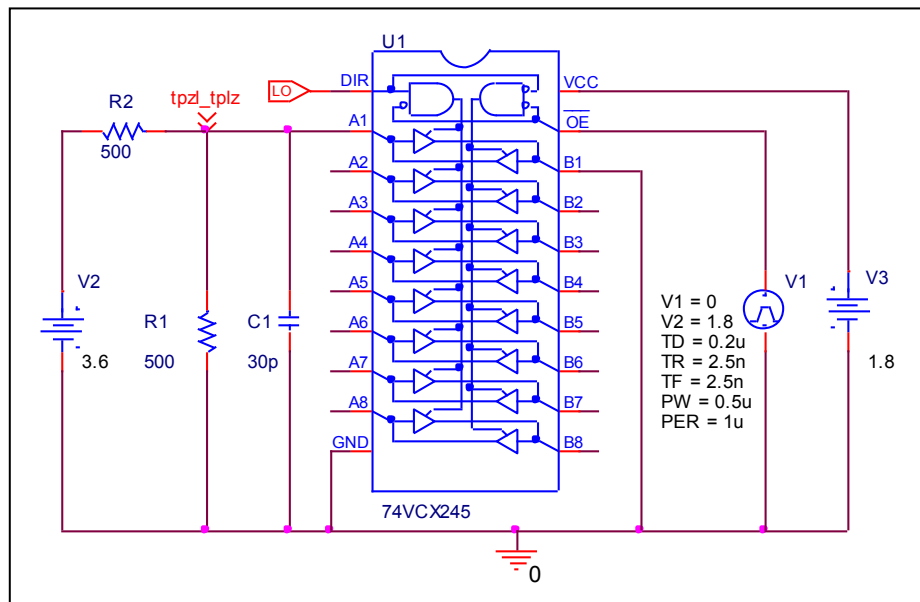
$V_{CC} = 1.5 \text{ V}$, $t_r = t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{PLZ} \text{ (ns)}$	14.4	14.127	-1.896
$t_{pZL} \text{ (ns)}$	19.6	19.441	-0.811

Output enable time (t_{pZL}) and Output disable time (t_{PLZ}) ($V_{CC} = 1.8$)

Circuit simulation result



Evaluation circuit

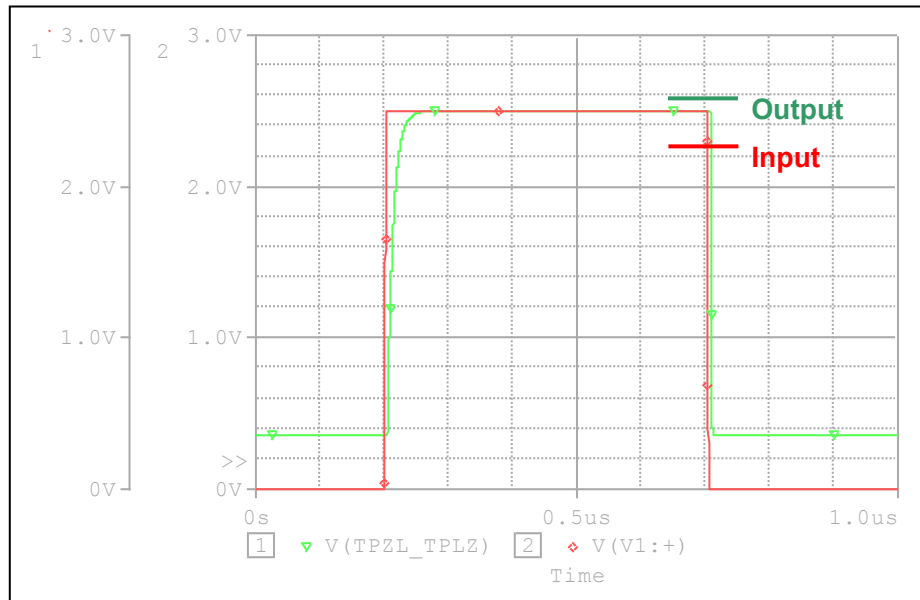


Comparison table $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$

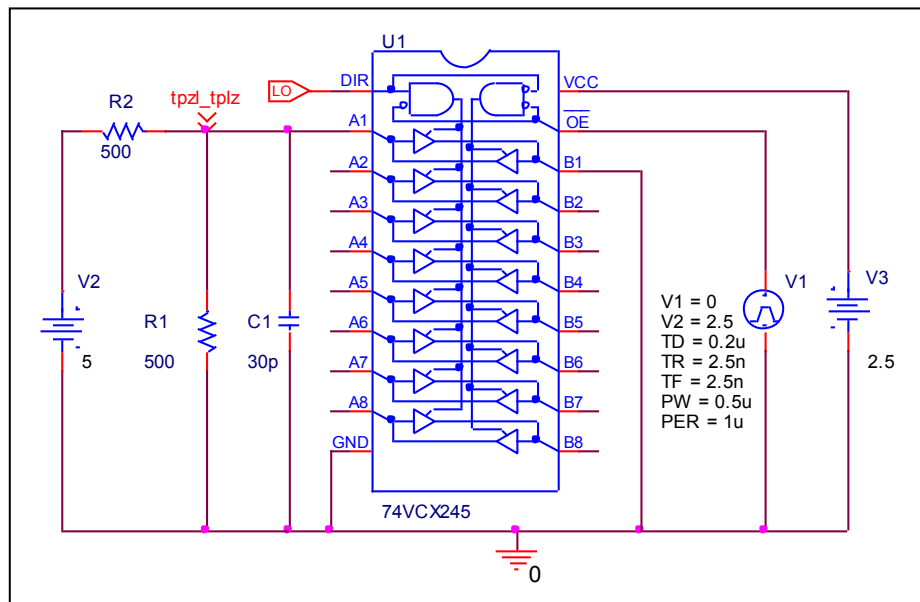
$V_{CC} = 1.8 \text{ V}$, $t_r = t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{PLZ} \text{ (ns)}$	7.2	7.0614	-1.925
$t_{pZL} \text{ (ns)}$	9.8	9.721	-0.806

Output enable time (t_{pZL}) and Output disable time (t_{PLZ}) ($V_{CC} = 2.5$)

Circuit simulation result



Evaluation circuit

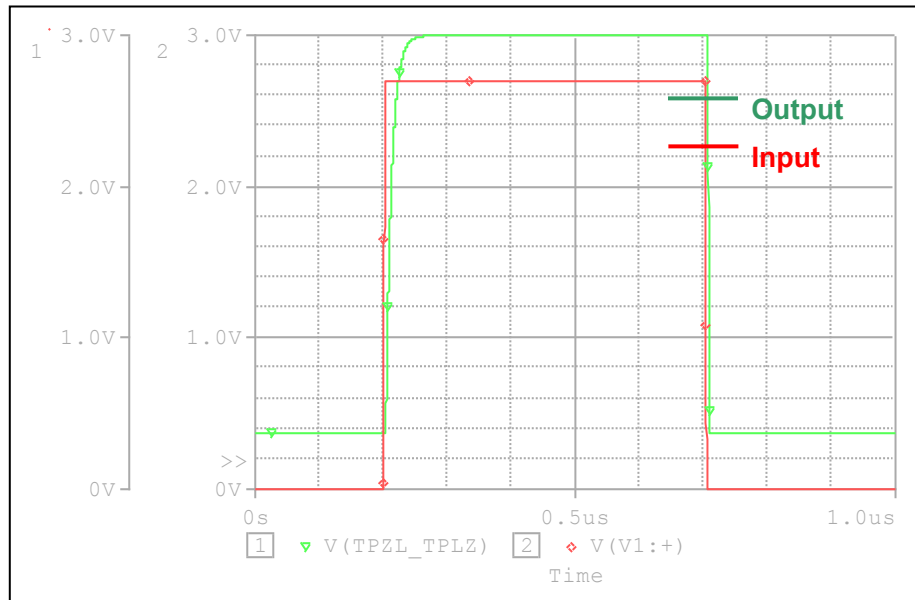


Comparison table $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$

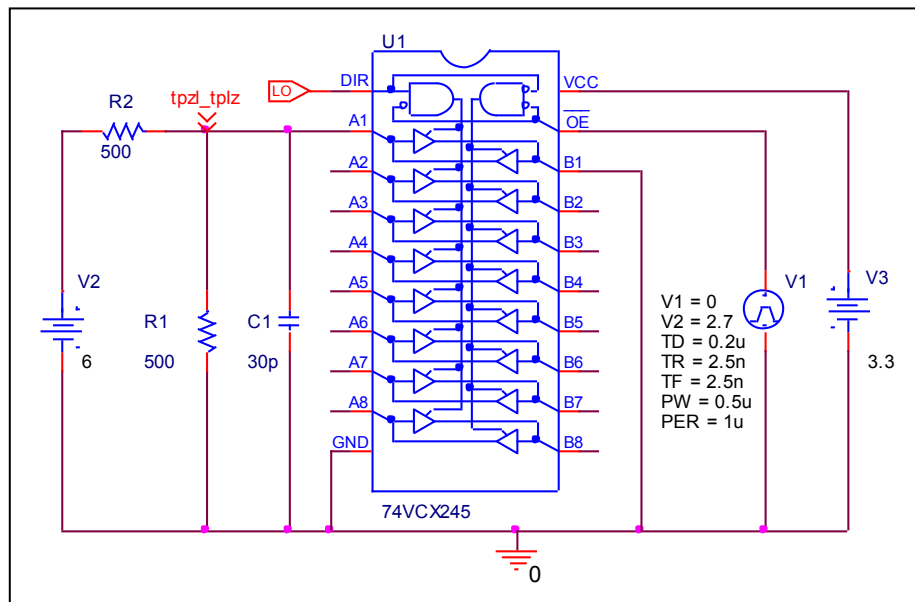
$V_{CC} = 2.5 \text{ V}$, $t_r = t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{PLZ} \text{ (ns)}$	4	3.9939	-0.153
$t_{pZL} \text{ (ns)}$	5.6	5.4786	-2.168

Output enable time (t_{pZL}) and Output disable time (t_{PLZ}) ($V_{CC} = 3.3$)

Circuit simulation result



Evaluation circuit



Comparison table $C_L = 30 \text{ pF}$, $R_L = 500 \Omega$

$V_{CC} = 3.3 \text{ V}$, $t_r=t_f = 2 \text{ ns}$	Measurement	Simulation	%Error
$t_{PLZ} \text{ (ns)}$	3.6	3.5963	-0.103
$t_{pZL} \text{ (ns)}$	4.5	4.4497	-1.118